

Thermal Management within PCB materials for the automotive industry

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Insulated Metal Substrate (IMS)

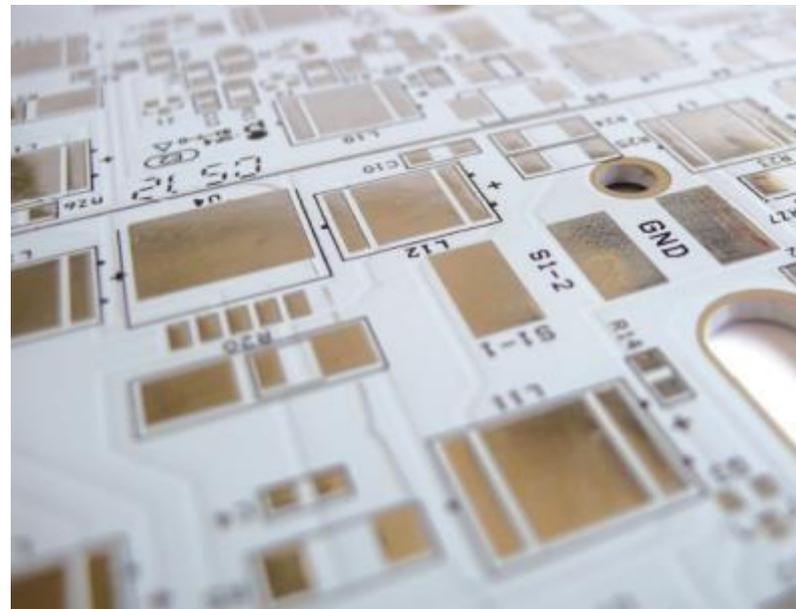
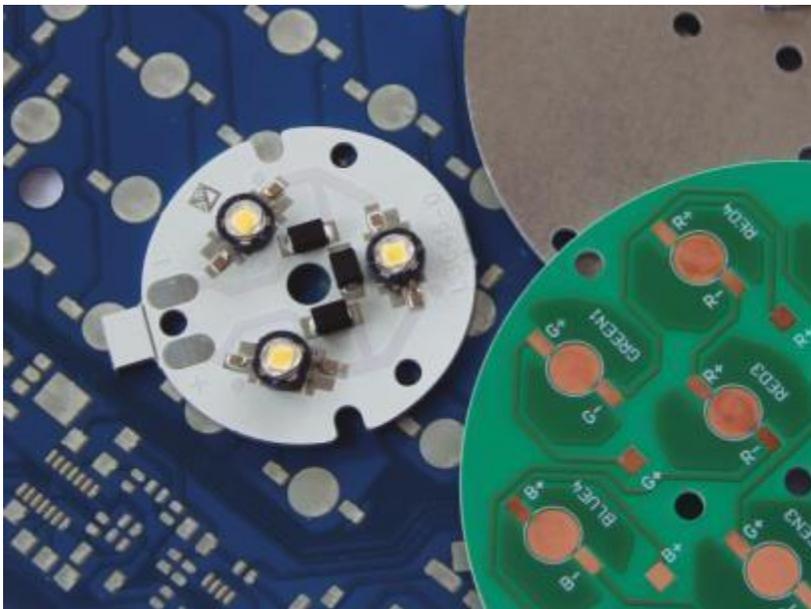


IMS

Thick aluminum based substrate, clad in ED copper foil.

Designed for an effective thermal dissipation and high electrical insulation.

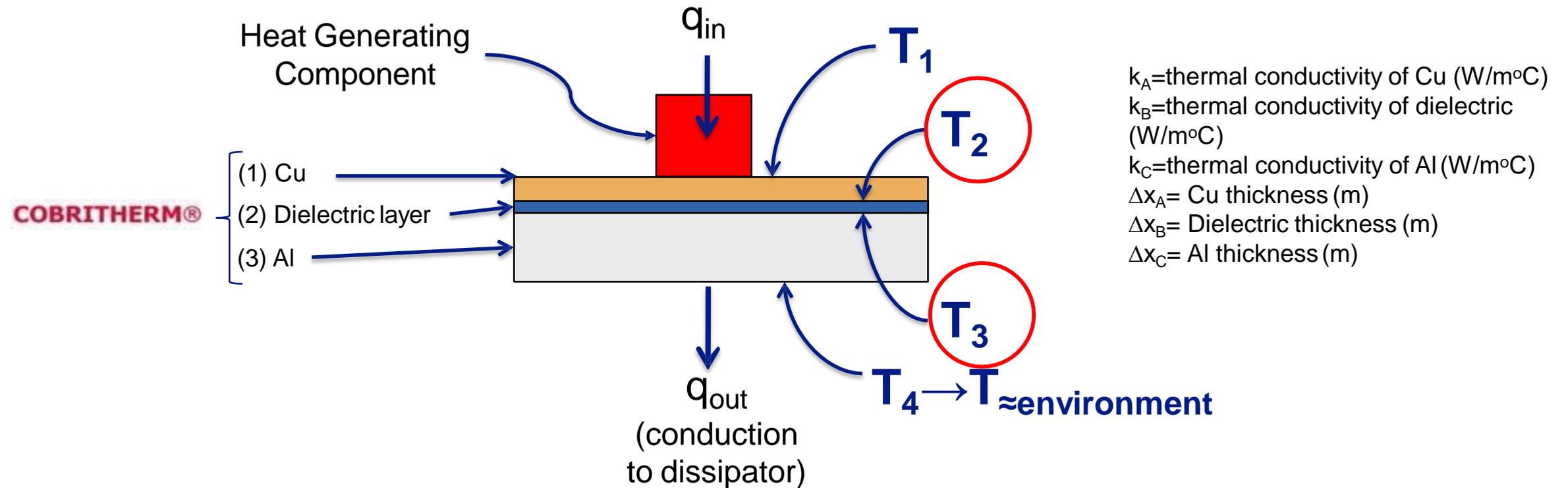
Our proprietary formulated polymer-ceramic, ensures high thermal conductivity, dielectric strength, and thermal endurance.



Insulated Metal Substrate allows:

- Processing by standard PCB procedures.
- Integrating heat dissipation with no need for extra components.
 - SMD assembly process.

Insulated Metal Substrate (IMS)



q , A , fixed by design.

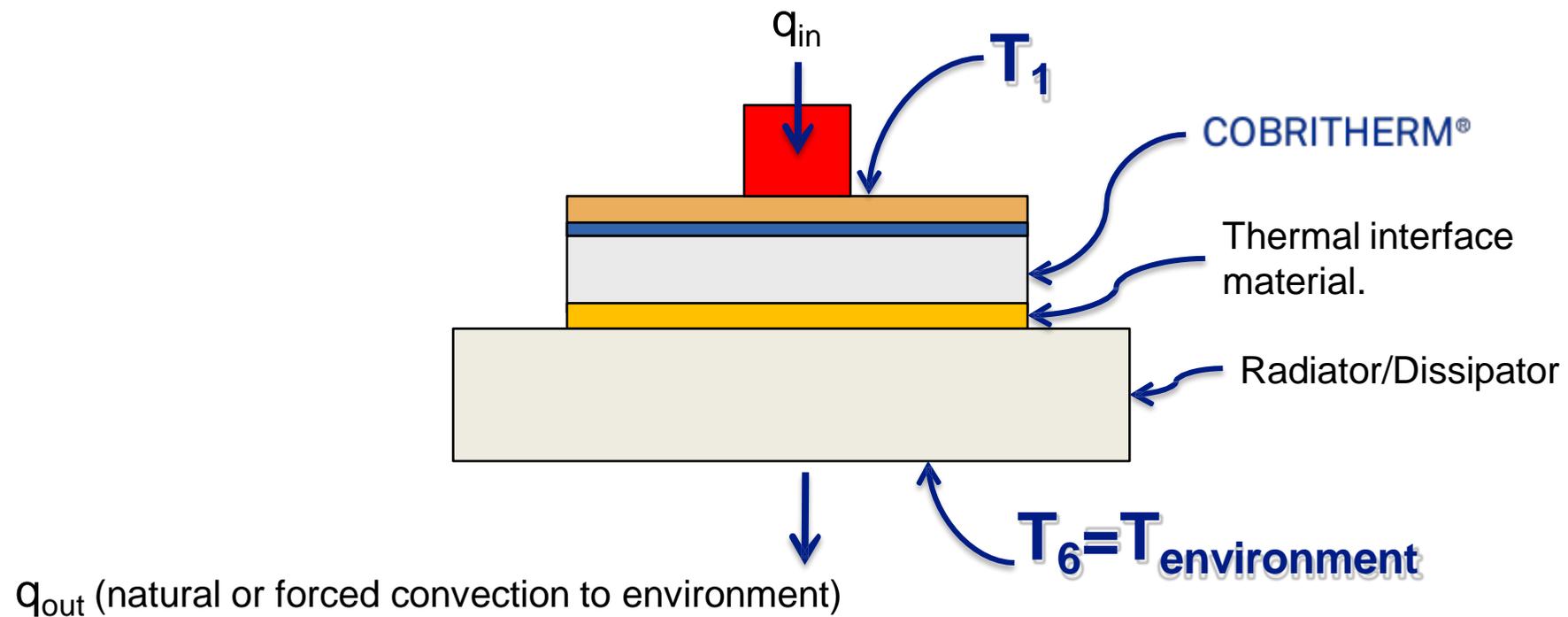
Ideally: $T_1 \rightarrow T_4$ (environment)

So: Small ΔX , Large k desired

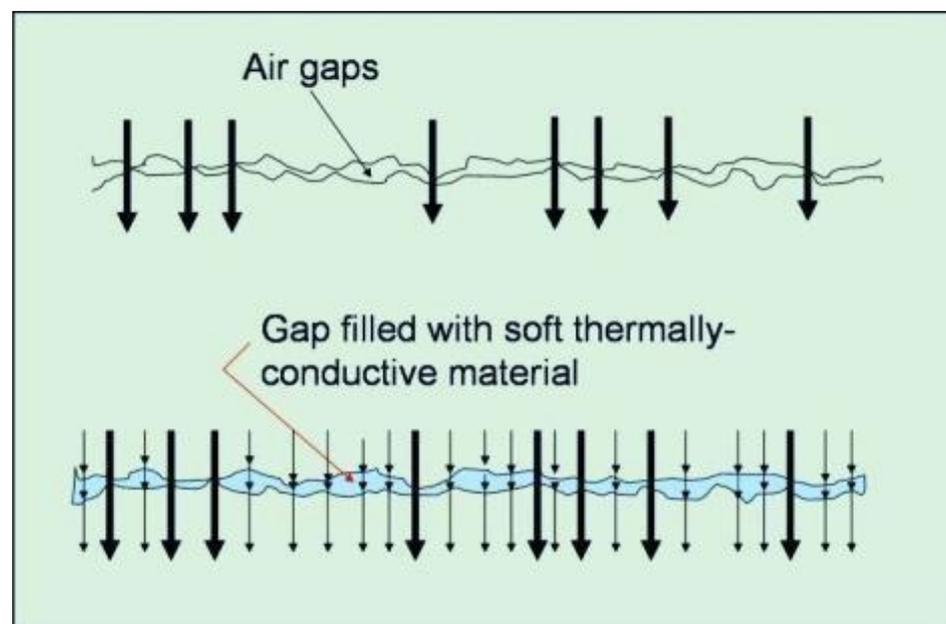
Limitations for ΔX : dielectric properties, conductivity, mechanical constraints, production limitations, etc.

Limitations for k : dielectric properties, material choice limitations.

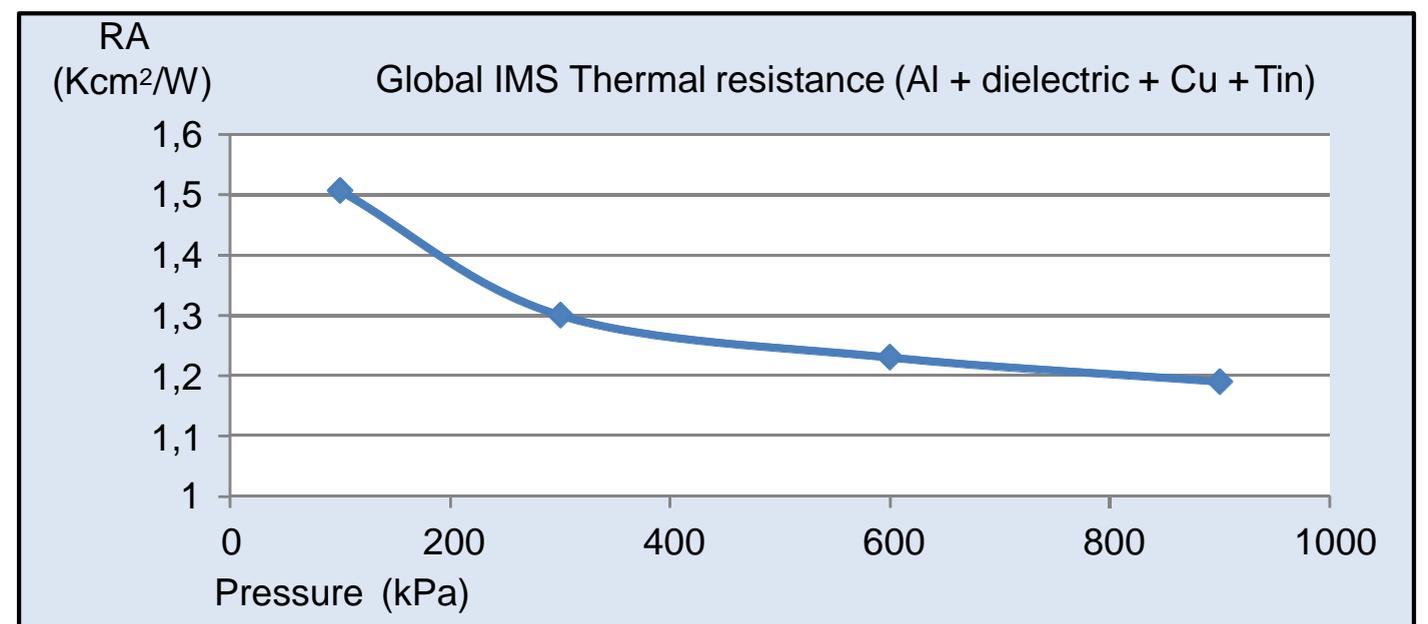
Insulated Metal Substrate (IMS)



Air gaps = Increased thermal resistance

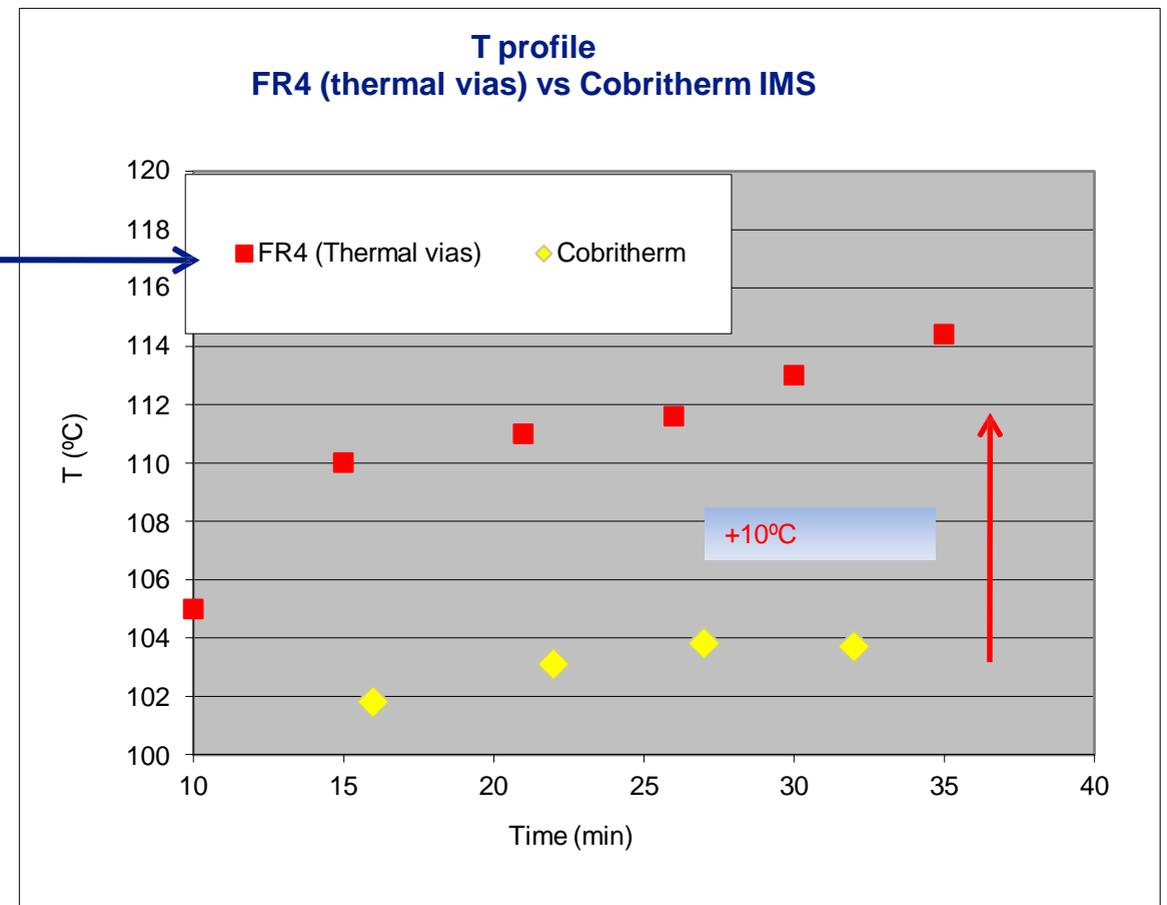
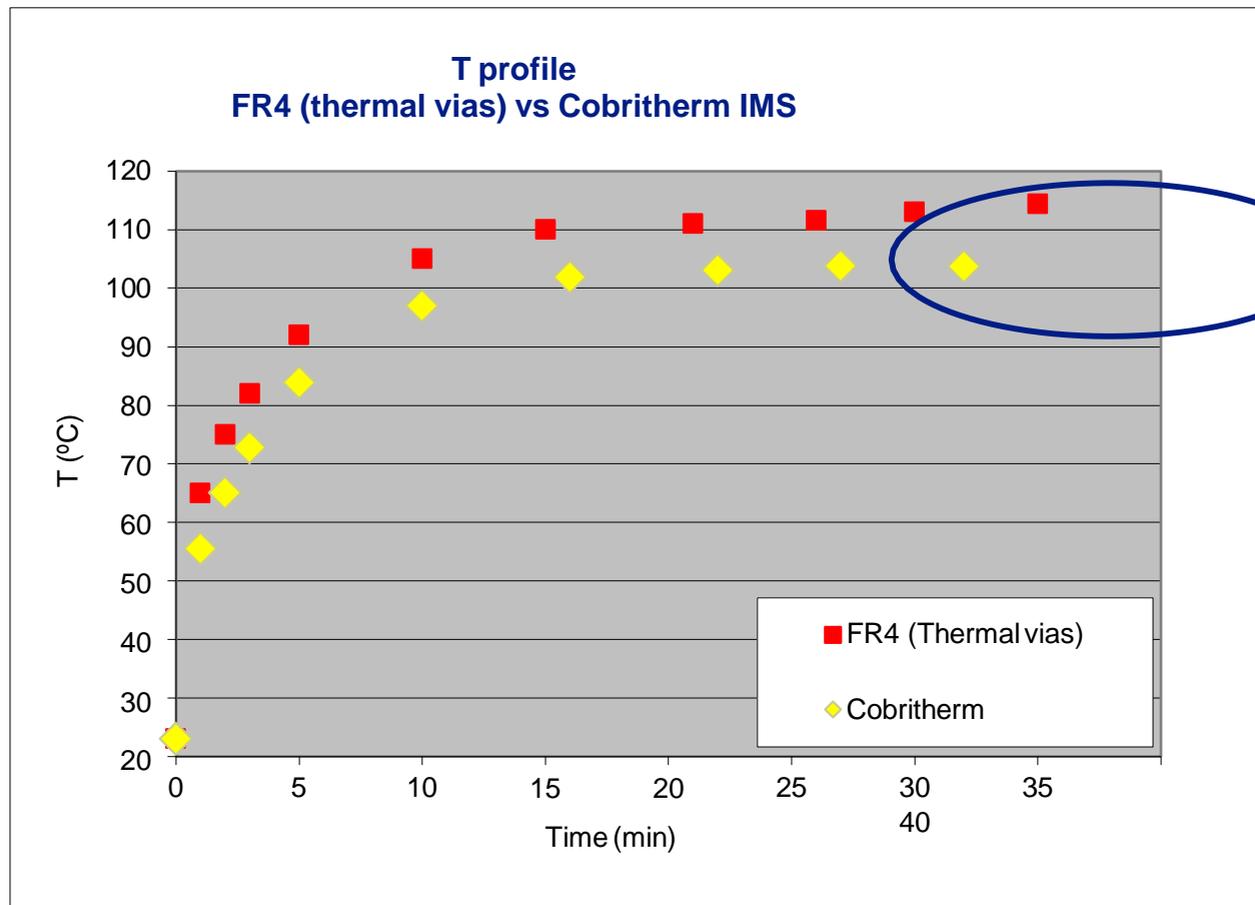


Thermal resistance and pressure

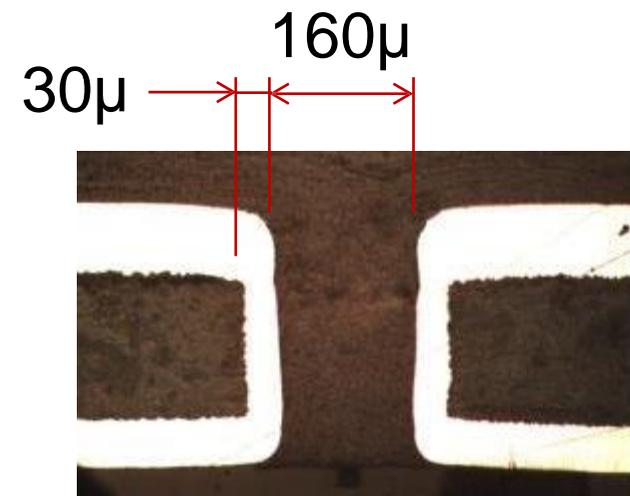


Thermal management

FR4 with thermal vias versus COBRITHERM®



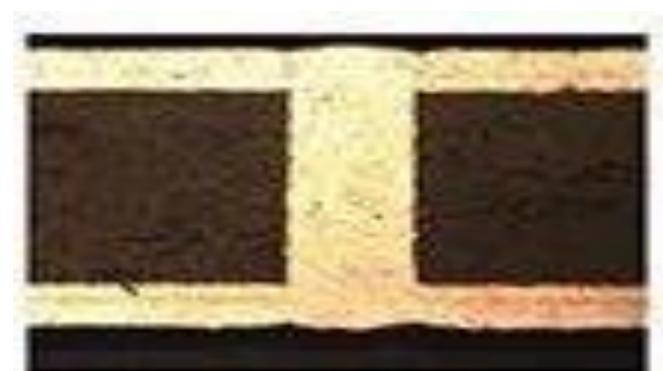
Thermal vias \neq Thermal filled vias



Thermal vias PTH 200μ

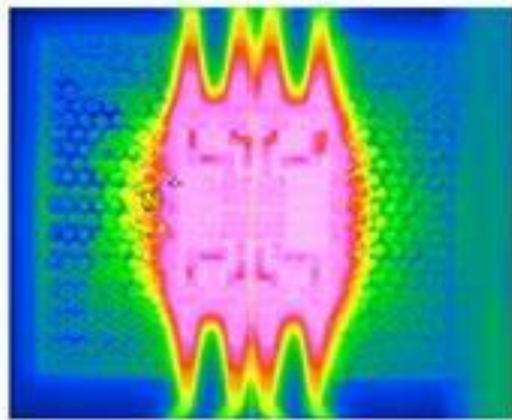


Filled thermal vias 150μ

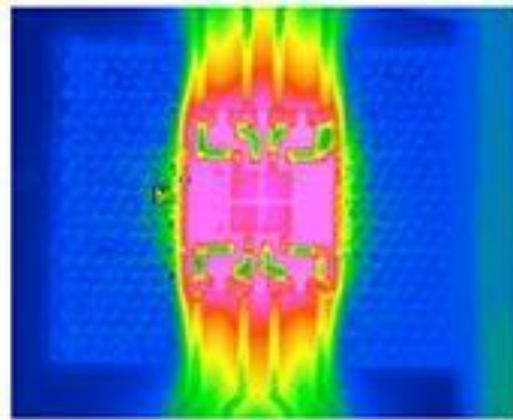


Thermal vias vs IMS

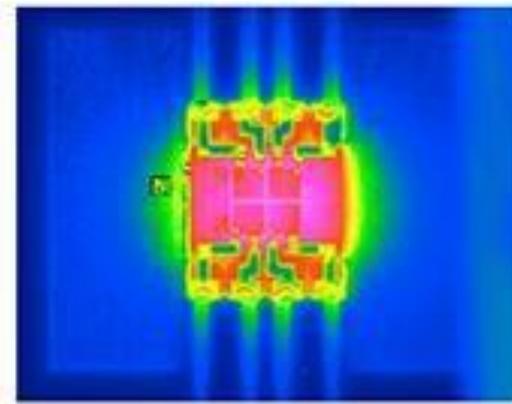
FR4 1mm
With thermal
vias



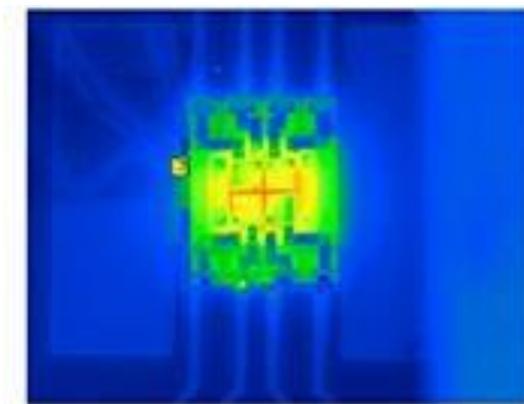
FR4 1mm
With filled
thermal vias



IMS
COBRITHERM
ALCUP – G NT



IMS
COBRITHERM
ULTRATHIN



Basic advantages of IMS COBRITHERM®

Perfect for cooling surface mount components

Insulating layer: high electrical insulation + thermal dissipation

Ideal for thermal dissipation

Very low thermal resistance

Greater robustness

Good PCB workability

Possibility of larger dimensions than DCBs

How do we make Cobritherm?

With **ALUMINUM**

Aluminium type 5052 or 6061: The most suitable for large series and mechanical processes.

With **COPPER**

Type of copper: Electrodeposited Copper (ED Copper) with special dendritic growth finishing.

METAL	Thermal Cond W/m [°] K	CTE ppm/°C	Density gr/cc
Aluminium	170	25	2.7
Copper	400	17	8.9

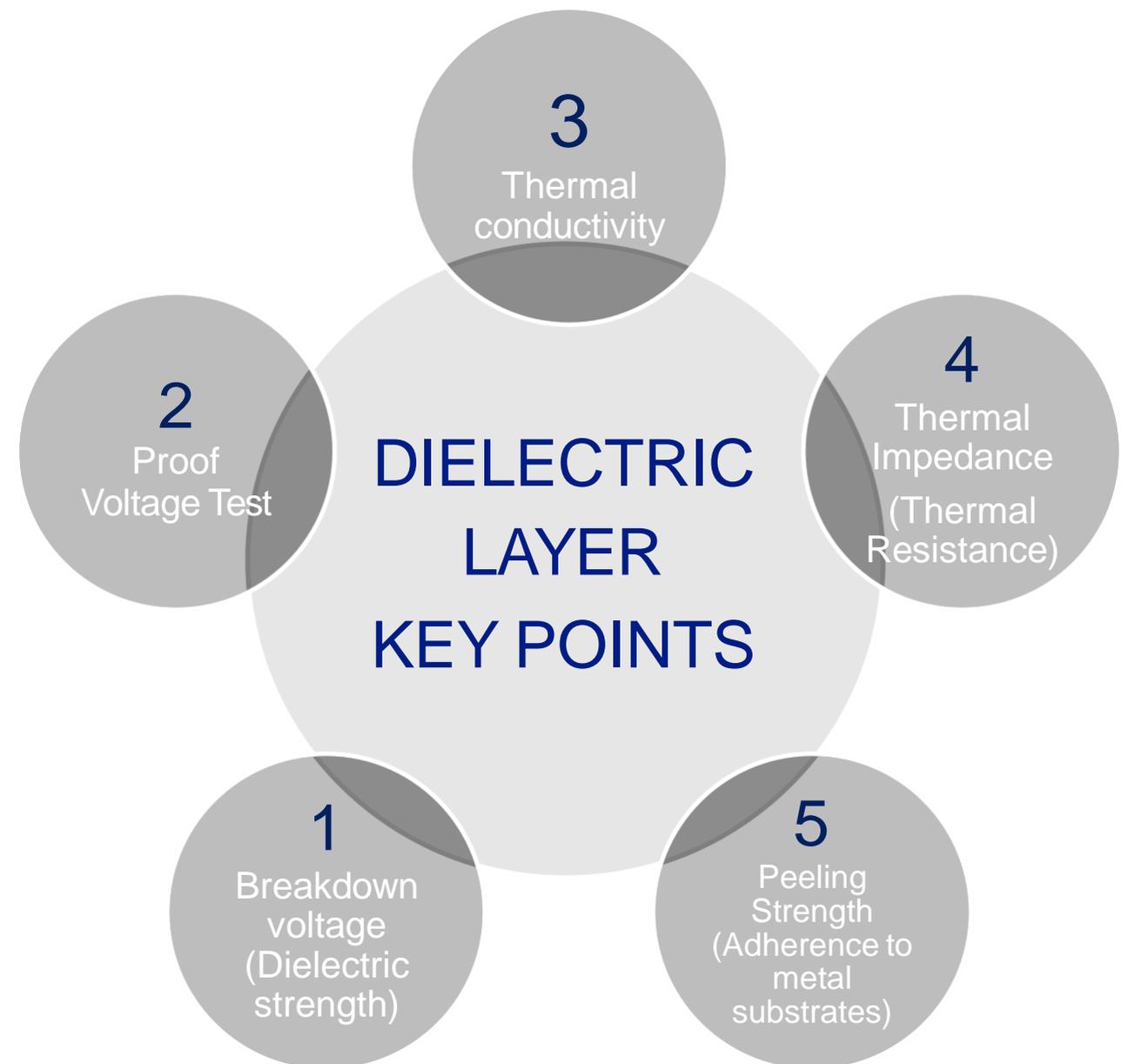
How do we make Cobritherm?

And with a **DIELECTRIC LAYER**:
The most important element in IMS

Organic resin, with ceramic filler to increase thermal conductivity

Filler type, size, shape, etc., determines IMS performances (%Filler-Polymer)

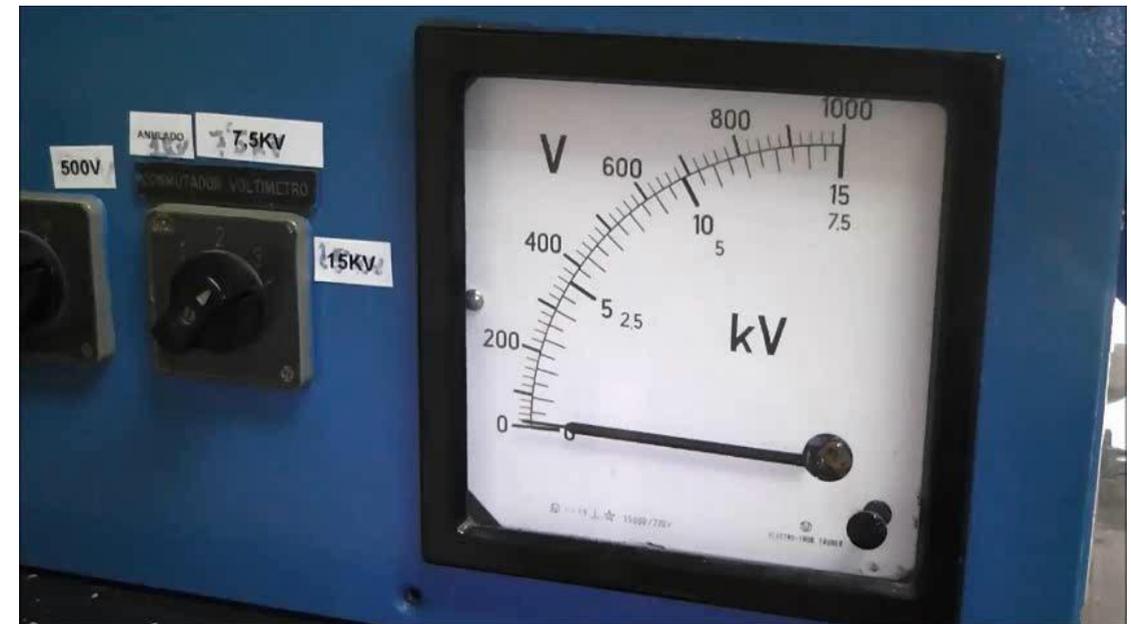
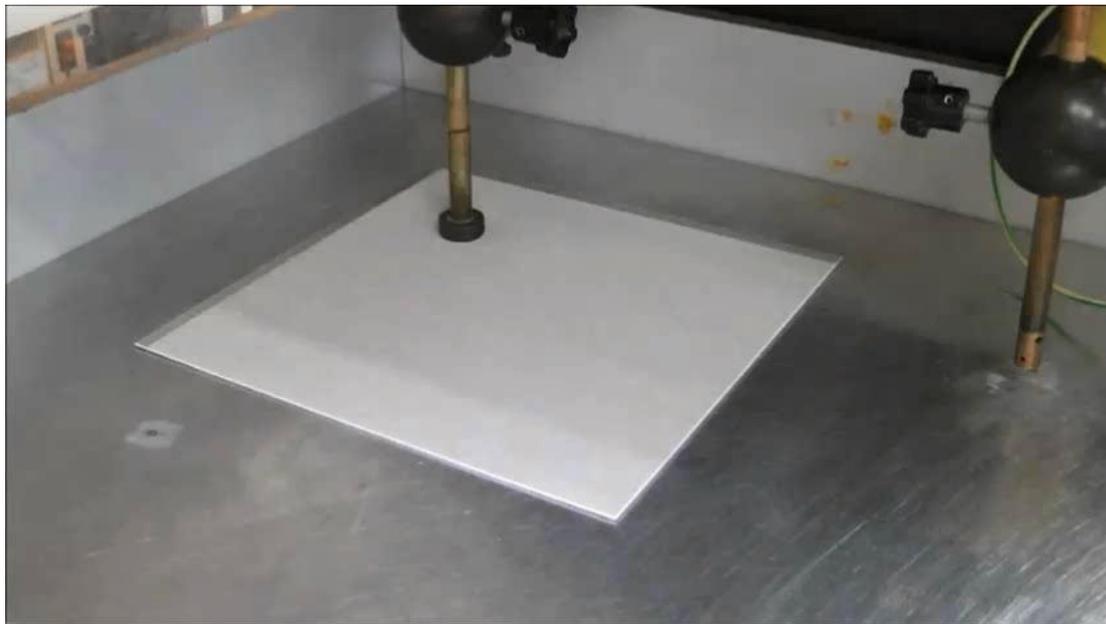
Usual ceramic fillers: Al_2O_3 , AlN, BN, ...



1

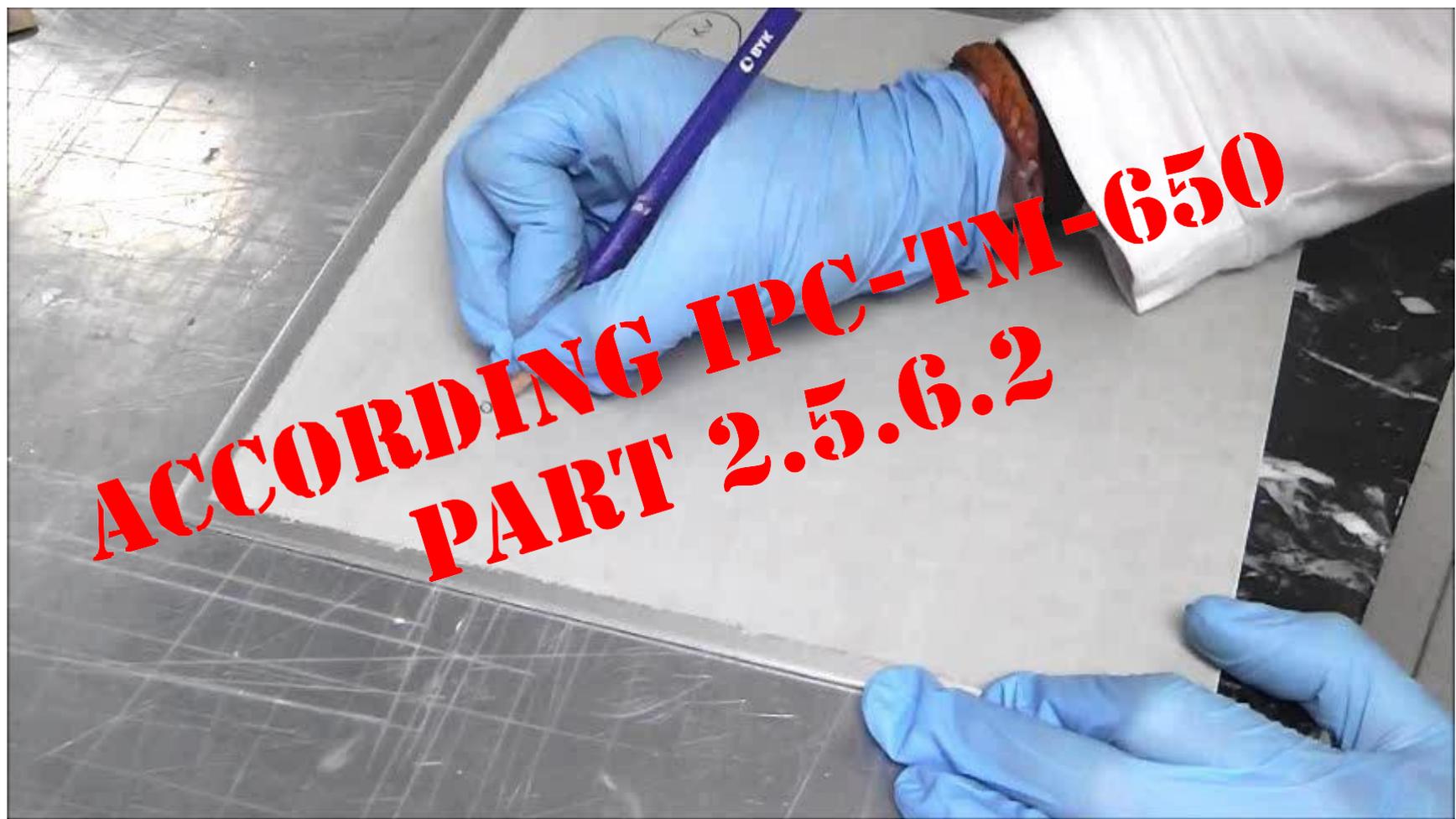
Breakdown voltage
(Dielectric strength)

Breakdown voltage (Dielectric strength)



1
Breakdown voltage
(Dielectric strength)

Breakdown voltage (Dielectric strength)
Performed according IPC-TM-650, part 2.5.6.2



$$\frac{9,25Kv + 9,0Kv + 9,5Kv + 9,0Kv + 8,3Kv}{5} = 9,01 Kv$$

The only worldwide IMS supplier that proof-tests 100% of its production

1

Breakdown
voltage

DIELECTRIC BREAKDOWN

Performed according to IPC-TM-650, part 2.5.6.2. Increases AC voltage until dielectric layer fails by electric short. Test is made on a relatively small surface area on the dielectric part using metal electrodes. Values obtained should be treated statistically, and are only a dielectric performance reference, not guaranteed values.

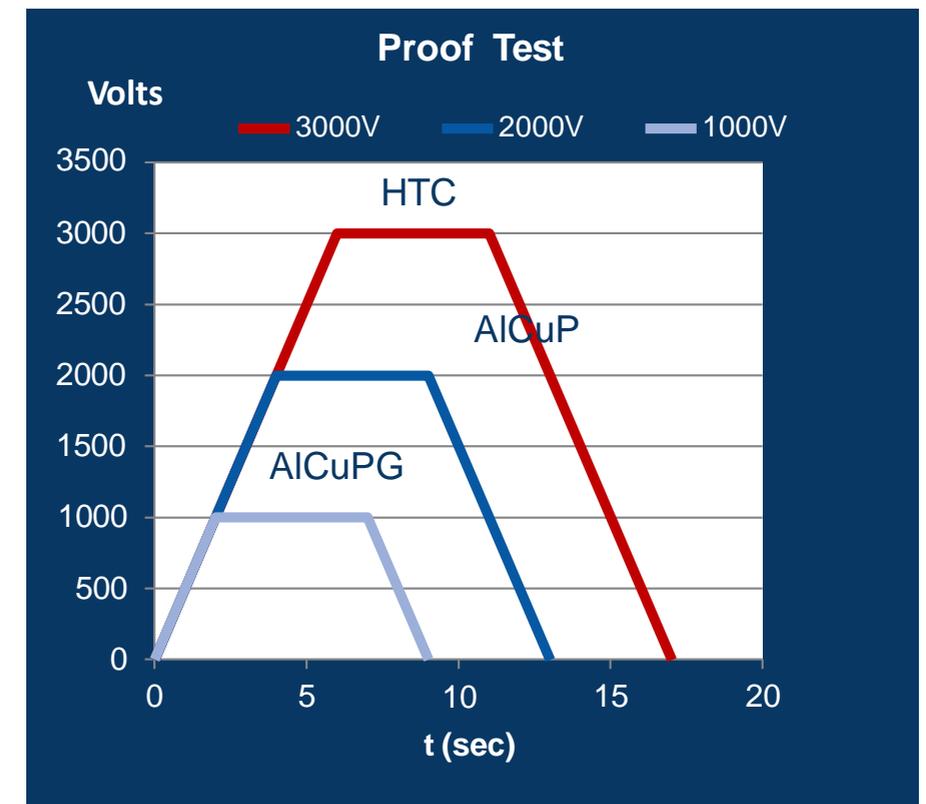
2

Proof
Voltage Test

ELECTRICAL PROOF TEST

Production electric control test, performed in 100% of the Cobritherm sheets: Exposes sheets to a DC (1000, 2000, 3000 V) electric field, raising it at 500 V/min. and holds voltage test for five seconds.

Proof-test from 1000 V DC to 3000 V DC:
guarantee for the dielectric request.



2

Proof
Voltage Test

Proof test / High Pot Test 3.000 V DC





Thermal Conductivity

Thermal Conductivity is the property of a material to conduct heat.
All materials have a thermal conductivity value.

Aluminum Oxide = 40 W/mK
Epoxy resin = 0,2 W/mK

Copper = 400 W/mK
Aluminum = 170 W/mK

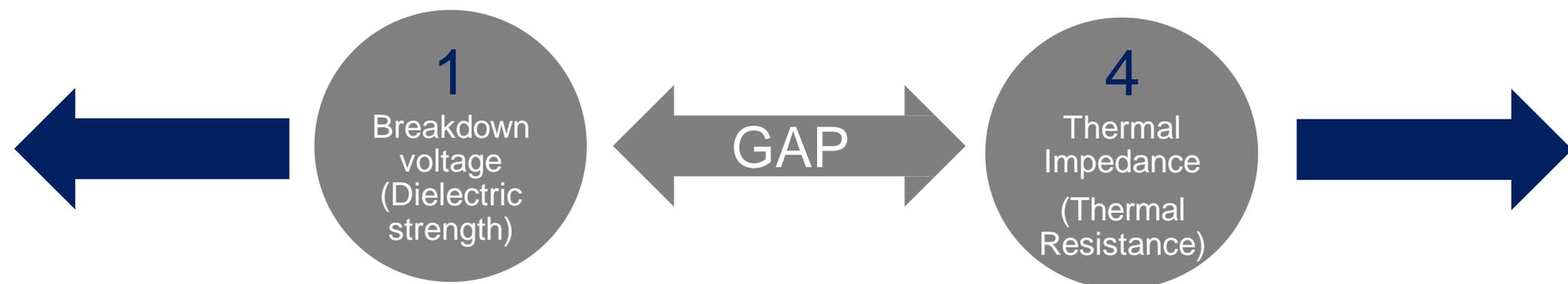
LED industry is focus on
thermal conductivity values



Thermal resistance is the
correct parameter to check

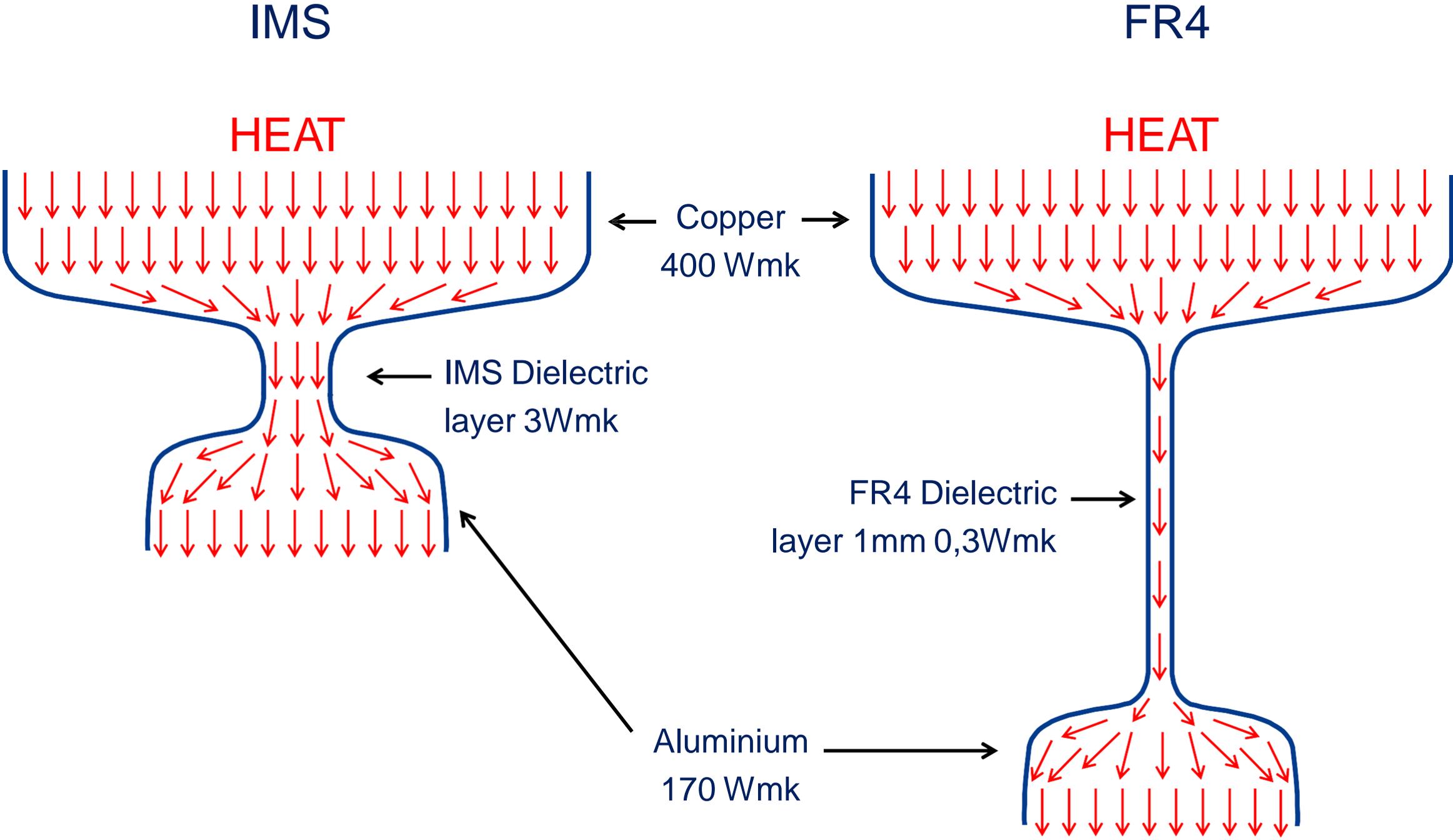
Dielectric Strength
«The thicker the better»

Thermal Resistance
«The thinner the better»



This is the challenge for IMS Suppliers

Main properties



4
Thermal Impedance
(Thermal Resistance)

Thermal resistance or Thermal impedance

	Thickness	Copper	Dielectric layer Thickness	Dielectric layer W/mK	Global Conductivity W/mK	Global Thermal resistance (Al+dielectric+Cu) °C/W	
FR4	1mm	35/00	1mm	0,3	0,3	11,11	
CEM-3	1mm	35/00	1mm	0,6	0,6	5,56	
AlCuP	1,5mm	35/00	120	1,8	21,3	0,260	→ 97% Reduction From FR4
HTC	1,5mm	35/00	130	2,2	23,7	0,234	
Ultrathin	1,5mm	35/00	35	3,2	70,9	0,074	→ 71% Reduction From AlCup
Flextherm	1,5mm	35/00	25	0,7	33,3	0,156	
Fastherm	1,5mm(1,4Al+0,1Cu)	35/00	0	--	141,1	0,035	→ 52% Reduction From Ultrathin

↓
99,7% Reduction
From FR4 to Fastherm

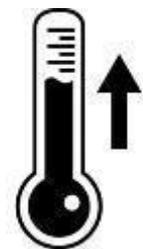
MOT Maximum Operation Temperature

A dielectric layer is an organic layer

An organic layer gets deteriorated with: **Time**



& Temperature



Constant high temperature will reduce 2 properties in the dielectric layer:

Dielectric strength

Copper adhesion to dielectric layer

$T_g \neq \text{MOT}$

T_g :

Glass transition: Is the reversible transition in amorphous materials from a hard and relatively brittle state into a molten or rubber-like state.

MOT:

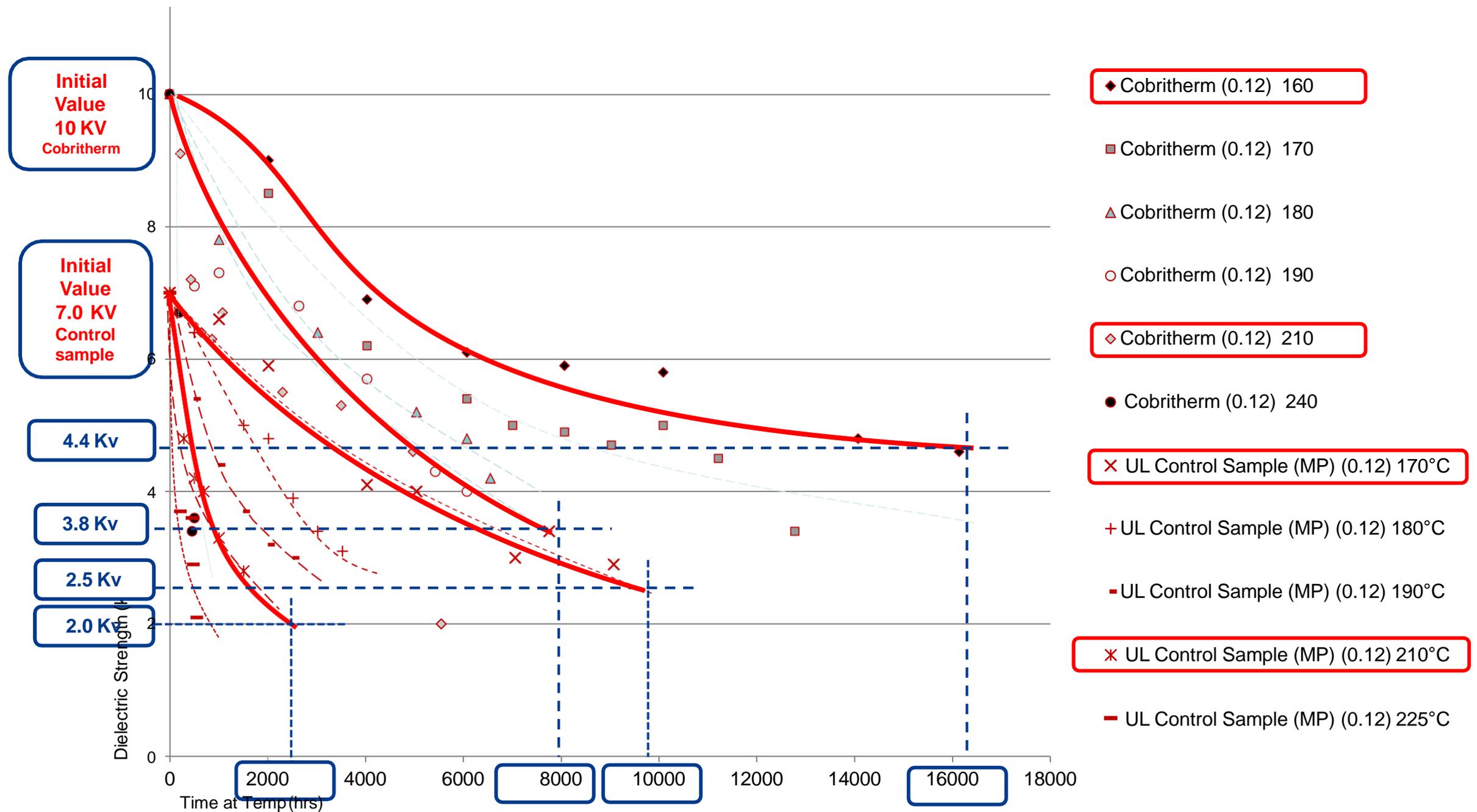
An operating temperature is the temperature at which the PCB operates. The PCB will operate effectively within a specified temperature range. Outside this range, the PCB lifetime is dramatically reduced or may fail.

Endurance limits – MOT values



UL Endurance Test – Industry Benchmark

Dielectric strength vs Time at Temperature
COBRITHERM vs Industry Benchmark



THERMAL CONDUCTIVITY

D5470 is the most suitable method vs E1461 for this kind of materials

Steady state measurements like D5470, usually yield the highest level of accuracy, on the order of +/-5-10%, meanwhile time domain techniques such as E1461, the relative uncertainties are on the order of 15-20%, and at time even larger errors.

	D5470	E1461
TECHNIQUE BASED	<ul style="list-style-type: none"> ∅ Steady state technique ∅ Time independent ∅ Direct measure of thermal resistance (apparent thermal conductivity) 	<ul style="list-style-type: none"> ∅ Pulsed (time domain) ∅ Time dependent
ASTM STANDARD RECOMMENDATION	∅ Electrical insulating materials for electronic applications	∅ Homogeneous isotropic materials
MAIN MEASURING DIFFERENCES	<ul style="list-style-type: none"> ∅ Temperature of measuring 25-50°C ∅ Temperature resolution 0.2K 	<ul style="list-style-type: none"> ∅ 400-600°C ∅ 0.05K
CONSIDERATIONS	∅ Interfacial thermal resistance can be calculated	∅ Heat capacity and density have to be calculated to carry out the test

THERMAL CONDUCTIVITY

SELECTED REASON FOR CHOOSING D5470 AS THE BEST METHOD FOR MEASURING THE THERMAL CONDUCTIVITY IN PCB WITH HIGH THERMAL CONDUCTIVITY

	D5470	E1461
	Specially recommended by ASTM for PCB laminates (ASTM D5074 paragraph 5.1)	No comments or instructions related to PCB samples.
TETS CONDITIONS	<ul style="list-style-type: none"> ∄ Values of conductivity measured at equal or similar electronics working temperature profile. ∄ Interfacial thermal resistances due to the contact between the sample and the equipment as well as the thermal oil, could be measured and excluded from the global resistance 	<ul style="list-style-type: none"> ∄ Only at high T could be carry out the measure. ∄ To reduce deviation high T are recommended (600°C) ∄ Laser time pulse must be adjusted based on thickness and nature of the sample. ∄ Only one standard ceramic thermal diffusivity reference is available with uncertainty 6%. ∄ Reference specimen and the unknown specimen must be very similar in size, proportions, emissivity and opacity. To assure the correct data, reference and the unknown must be tested very close to each other, both temporally (minutes) and thermally (strictly at the same temperature). ∄ Large number of repeat experiments is needed to reduce random errors

THERMAL CONDUCTIVITY

SAMPLE	<ul style="list-style-type: none"> ⊘ Useful method for ceramics, metals and plastics ⊘ Useful for heterogeneous materials 	<ul style="list-style-type: none"> ⊘ Only for homogenous isotropic and solid materials. ⊘ Heterogeneous and anisotropic materials frequently produce erroneous data.
	<ul style="list-style-type: none"> ⊘ No sample preparation is needed ⊘ Built up metal base laminate is measured (metal base + dielectric + copper ED) ⊘ Samples with reduced thickness or really too thin could be measured 	<ul style="list-style-type: none"> ⊘ Coating of the specimen with very thin uniform graphite or other high emissivity coating on both faces is required previous to measuring. ⊘ Metal base laminate by itself is not possible to be measured ⊘ Thickness of the sample must be 1-6mm (only dielectric). ⊘ Really big difference thickness between the sample measured and the real built up PCB laminate ⊘ Only dielectric layer alone can be measured

RESULTS	<ul style="list-style-type: none"> ⊘ Thermal resistance due to internal interfaces are considered (internal built up of the metal base laminate, such as interface between dielectric layer and metal base and copper ED) ⊘ Only the thickness of the sample as an external parameter is needed to carry out the calculation of thermal conductivity. 	<ul style="list-style-type: none"> ⊘ Porosity of the material produce mistakes in the lecture ⊘ Heat capacity and density of the specimen it is necessary to measure previously to obtain thermal conductivity. <ul style="list-style-type: none"> a) This method tends to give erroneous results for specific heat capacity for materials with large anisotropy (typically composites with directional structures). b) Density may be calculated. Error is included due to density is a thermal dependent parameter, and normally is measured at room temperature, and not at 400-600°C (T used for calculation) c) Increasing of uncertainty due to accumulative measure errors
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METHOD DESCRIPTION

D5470

This state technique is based on heat conduction between two parallel, isothermal surfaces separated by a test specimen of uniform thickness. The thermal gradient imposed on the specimen causes the heat flow. Apparent thermal conductivity is directly obtained from this data and the thickness of the specimen. **Fig 1**

E1461

A small, disc specimen is subjected to a high intensity duration radiant energy. The energy of the pulse is absorbed on the front surface of the specimen and the resulting rear face temperature rise (thermal curve) is recorded. The thermal diffusivity value is calculated from the specimen thickness and the time required for the rear face temperature rise to reach a percentage of its maximum value. **Fig 2**

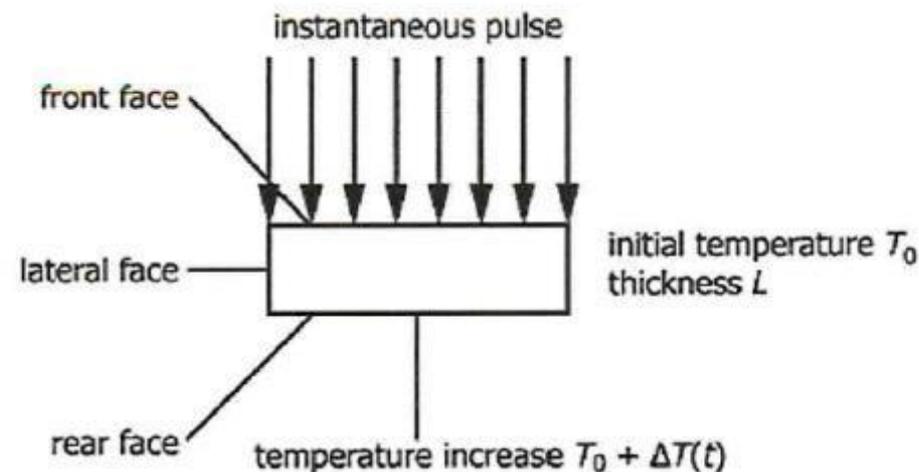


Fig 2 E1461 Schematic for the Flash method

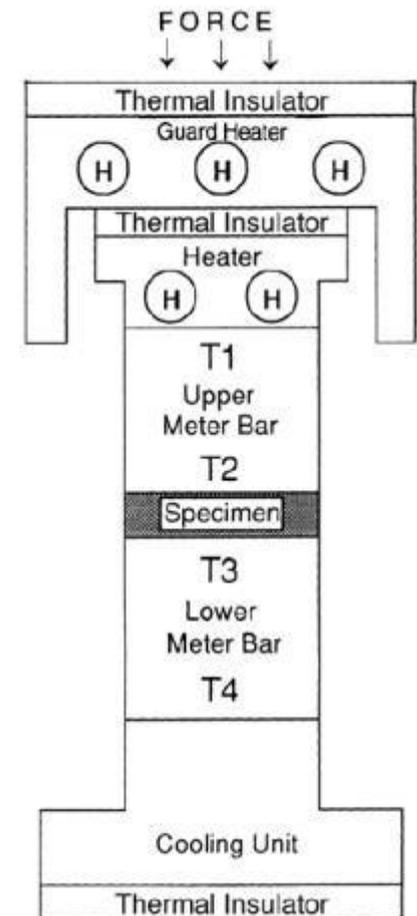
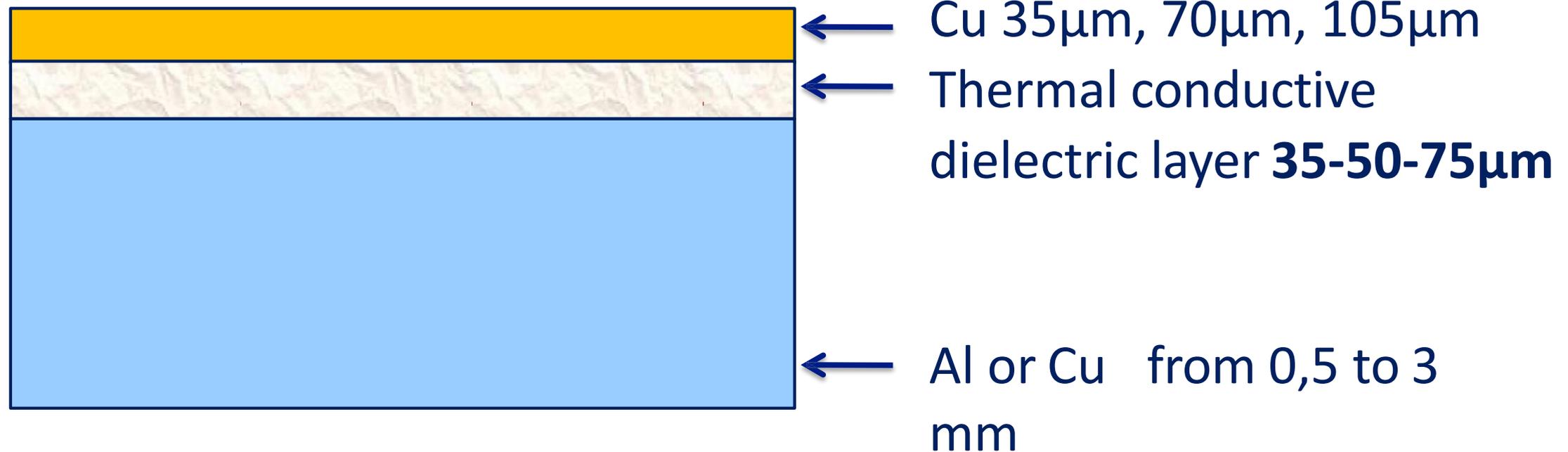


Fig 1 D-5470 Schematic equipment. Guarded Heater Test Stack

COBRITHERM® ULTRATHIN 35-50-75µm



HTC ULTRATHIN COMPOSITION



RANGE

HTC ULTRA-THIN

- Provides higher thermal performance
- Excellent working temperature.
- Dielectric thickness of 35,50 and 75 µm.
- Thermal resistance Ultrathin 35µm down to 0,11 Kcm²/W (0,017 Kinch²/W).
- Thermal resistance Ultrathin 50µm down to 0,15 Kcm²/W (0,024 Kinch²/W).
- Thermal resistance Ultrathin 75µm down to 0,23 Kcm²/W (0,036 Kinch²/W).
- Offers excellent thermal dissipation conditions for high power LED applications.

	Composition				Dielectric layer					
	Aluminium		Copper		Thickness		Conductivity		Thermal impedance	
							1	2	3	4
	mm	inch	mic	Onz	mic	(mil)	W/mK	W/inchK	Kcm ² /W	Kinch ² /W
Ultrathin 35µm	1,5	0,059	35	1	35	1,4	3,2	0,081	0,109	0,017
Ultrathin 50µm	1,5	0,059	35	1	50	2,0	3,2	0,081	0,156	0,024
Ultrathin 75µm	1,5	0,059	35	1	75	3,0	3,2	0,081	0,234	0,036

COBRITHERM® HTC ULTRA-THIN

- Provides higher thermal performance.
- Excellent working temperature.
- Dielectric thickness of only 35 microns.
- Thermal resistance down to 0,11 Kcm²/W (0,017 Kinch/W) which offers excellent thermal dissipation conditions for high power LED applications.

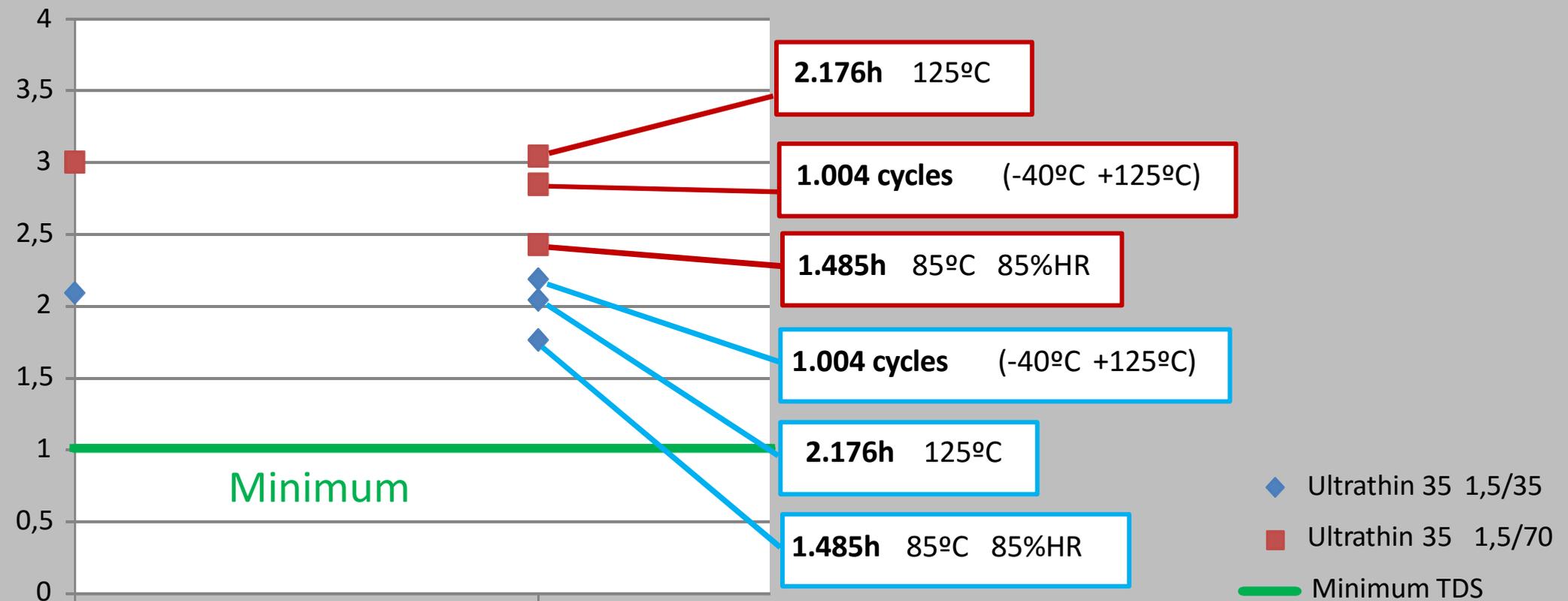


	Composition				Dielectric layer						
	Aluminium		Copper		Thickness		Conductivity		Thermal impedance		
							1	2	3	4	5
	mm	inch	mic	Onz	mic	(mil)	W/mK	W/inchK	Kcm ² /W	Kinch ² /W	°C/W
Ultrathin 35µm	1,5	0,059	35	1	35	1,4	3,2	0,081	0,109	0,017	0,036
Ultrathin 50µm	1,5	0,059	35	1	50	2,0	3,2	0,081	0,156	0,024	0,052
Ultrathin 75µm	1,5	0,059	35	1	75	3,0	3,2	0,081	0,234	0,036	0,078

Aging cycles

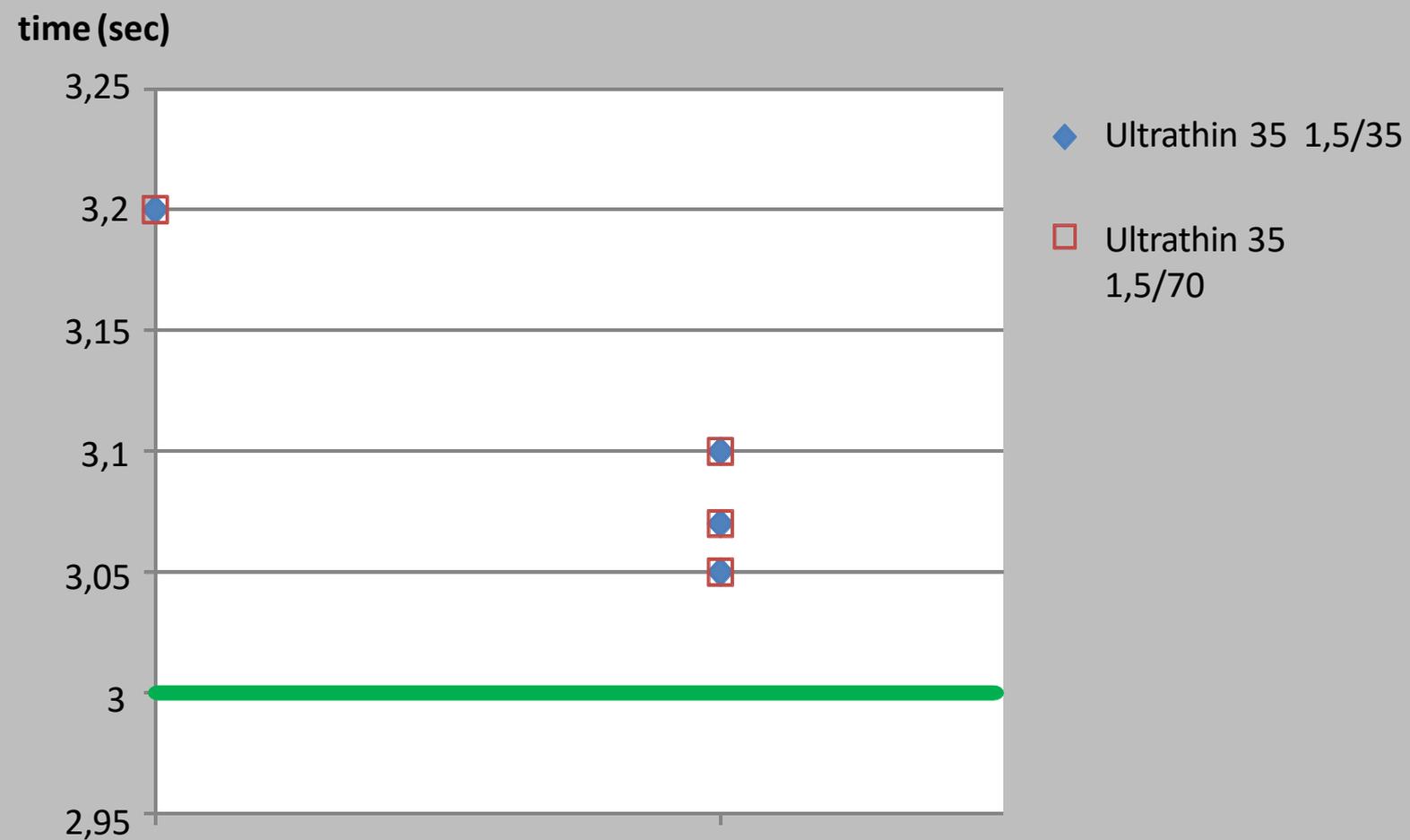
Peel strength (after thermal stress floating 20sec & 288°C)

N/mm



Aging cycles

Conductivity after thermal aging



ULTRATHIN 35µm

DATA SHEET

DS_160208

COBRITHERM HTC 3,2W 35 ULTRA THIN LAYER (PROOF TEST 1000V)

DESCRIPTION

Insulated Metal Substrate (IMS), based aluminum clad with ED copper foil on the opposite side. It is designed for the reliable thermal dissipation of circuitry. A proprietary formulated polymer-ceramic ultra thin bonding layer with high thermal conductivity and dielectric strength allows us to guarantee thermal endurance.

The material is supplied with a film on the aluminum side to protect it against wet PCB processes.

ROHS compliance directive 2002/95/EC and REACH N° 1907/2006

STANDARD CONSTRUCTIONS

Aluminum thickness, m (in)	1000 (0.039) – 1500 (0.059) – 2000 (0.078) – 3000 (0.12)	Aluminium Alloy / Treat	5052
Insulation thickness, m	35 micron (1,37 mils)	Dielectric thickness tolerance	± 10 m (0,4mils)
ED copper thickness, m	35 (1oz) – 70 (2oz) – 105 (3oz) - 210 (6oz)		

Other constructions available upon request

UL Approved , QMTS2, QMTS8 File: E47820

IPC 4101

- (1) **Electrical proof test. 100% of our laminate production delivered, has been “on line” verified at 1000v**
V_{dc}: 500 V/sec. ramp // 5sec.

PROPERTIES	TEST METHOD	UNITS	TYPICAL VALUES	Guaranteed values
1500 m Al / 35 m dielectric / 70 m Cu				
Time to blister at 288°C, floating on solder (50 x 50 mm)	IEC-61189	Sec	>120	>60
Copper Peel strength, after heat shock 20 sec/288°C (Cu 70mic)	IPC-TM 650-2.4.8	N/mm (Lb/in)	2,0 (16,0)	>1,5 (>10,3)
Dielectric breakdown voltage, AC (2)	IPC-TM 650-2.5.6.3	kV	3	2.5
Proof Test, DC (1)	--	V	1000	1000
Thermal conductivity (dielectric layer)	ASTM-D 5470	W/mK (W/inK)	3,20 (0,081)	3,00 (0,076)
Thermal impedance (dielectric layer) HTC 35	ASTM-D 5470	Kcm ² /W (Kin ² /W)	0,11 (0,017)	0,12 (0,018)
Surface resistance after damp heat and recovery	IEC-61189	MΩ	10 ⁵	10 ⁵
Volume resistivity after damp heat and recovery	IEC-61189	MΩm	10 ⁴	10 ⁴
Relative permittivity after damp heat and recovery, 10 kHz	IEC-61189	-	4,5	4,5
Dissipation factor after damp heat and recovery 10 kHz	IEC-61189	-	0,02	0,02
Comparative tracking index (CTI)	IEC-61112	V	600	>550
Permittivity	--	pF/m (pF/in)	6,7 (39,4)	6,7 (39,4)
Flammability, according UL-94, class	UL-94	class	V-0	V-0
Glass transition temperature of dielectric layer (by TMA)	IPC-TM 650-2.4.24	°C	120	120
Maximum operating temperature	--	°C	150	150

ULTRATHIN 50 µm

DATA SHEET

DS_160307

COBRITHERM HTC 3,2W 50 mic ULTRA THIN LAYER (PROOF TEST 750V)

DESCRIPTION

Insulated Metal Substrate (IMS), based aluminum clad with ED copper foil on the opposite side. It is designed for the reliable thermal dissipation of circuitry. A proprietary formulated polymer-ceramic ultra thin bonding layer with high thermal conductivity and dielectric strength allows us to guarantee thermal endurance.

The material is supplied with a film on the aluminum side to protect it against wet PCB processes.

ROHS compliance directive 2002/95/EC and REACH N° 1907/2006

STANDARD CONSTRUCTIONS

Aluminum thickness, m (in)	1000 (0.039) – 1500 (0.059) – 2000 (0.078) – 3000 (0.12)	Aluminum Alloy / Treat	5052
Insulation thickness, m	50 micron (2 mils)	Dielectric thickness tolerance	+ 20 m (0,8mils)
ED copper thickness, m	35 (1oz) – 70 (2oz) – 105 (3oz) - 210 (6oz)		

Other constructions available upon request

UL Approved , QMTS2, QMTS8 File: E47820

IPC 4101

(1) Electrical proof test. 100% of our laminate production delivered, has been “on line” verified at 750V

PROPERTIES	TEST METHOD	UNITS	TYPICAL VALUES	Values
1500 m Al / 50 mic dielectric / 70 mic Cu				
Time to blister at 288°C, floating on solder (50 x 50 mm)	IEC-61189	Sec	>120	>60
Copper Peel strength, after heat shock 20 sec/288°C (Cu 35mic)	IPC-TM 650-2.4.8	N/mm (Lb/in)	1,5 (8,5)	>1,0 (>5,7)
Dielectric breakdown voltage, AC (2)	IPC-TM 650-2.5.6.3	kV	2,5	2,0
Proof Test, DC (1)	--	V	750	750
Thermal conductivity (dielectric layer)	ASTM-D 5470	W/mK (W/inK)	3,20 (0,081)	3,00 (0,076)
Thermal impedance (dielectric layer)	ASTM-D 5470	Kcm ² /W (Kin ² /W)	0,16 (0,024)	0,17 (0,026)
Comparative tracking index (CTI)	IEC-61112	V	600	>550
Flammability, according UL-94, class	UL-94	class	V-0	V-0
Glass transition temperature of dielectric layer (by TMA)	IPC-TM 650-2.4.24	°C	120	120
Maximum operating temperature	--	°C	150	150

ULTRATHIN 75 µm

DATA SHEET

DS_160307

COBRITHERM HTC 3,2W 75 mic ULTRA THIN LAYER (PROOF TEST 750V)

DESCRIPTION

Insulated Metal Substrate (IMS), based aluminum clad with ED copper foil on the opposite side. It is designed for the reliable thermal dissipation of circuitry. A proprietary formulated polymer-ceramic ultra thin bonding layer with high thermal conductivity and dielectric strength allows us to guarantee thermal endurance.

The material is supplied with a film on the aluminum side to protect it against wet PCB processes.

ROHS compliance directive 2002/95/EC and REACH N° 1907/2006

STANDARD CONSTRUCTIONS

Aluminum thickness, m (in)	1000 (0.039) – 1500 (0.059) – 2000 (0.078) – 3000 (0.12)	Aluminum Alloy / Treat	5052
Insulation thickness, m	75 micron (2 mils)	Dielectric thickness tolerance	+ 20 m (0,8mils)
ED copper thickness, m	35 (1oz) – 70 (2oz) – 105 (3oz) - 210 (6oz)		

Other constructions available upon request

UL Approved , QMTS2, QMTS8 File: E47820

IPC 4101

(1) Electrical proof test. 100% of our laminate production delivered, has been “on line” verified at 750V

PROPERTIES	TEST METHOD	UNITS	TYPICAL VALUES	Values
1500 m Al / 50 mic dielectric / 70 mic Cu				
Time to blister at 288°C, floating on solder (50 x 50 mm)	IEC-61189	Sec	>120	>60
Copper Peel strength, after heat shock 20 sec/288°C (Cu 35mic)	IPC-TM 650-2.4.8	N/mm (Lb/in)	1,5 (8,5)	>1,0 (>5,7)
Dielectric breakdown voltage, AC (2)	IPC-TM 650-2.5.6.3	kV	3,5	3,0
Proof Test, DC (1)	--	V	750	750
Thermal conductivity (dielectric layer)	ASTM-D 5470	W/mK (W/inK)	3,20 (0,081)	3,00 (0,076)
Thermal impedance (dielectric layer)	ASTM-D 5470	Kcm ² /W (Kin ² /W)	0,23 (0,016)	0,25 (0,039)
Comparative tracking index (CTI)	IEC-61112	V	600	>550
Flammability, according UL-94, class	UL-94	class	V-0	V-0
Glass transition temperature of dielectric layer (by TMA)	IPC-TM 650-2.4.24	°C	120	120
Maximum operating temperature	--	°C	150	150

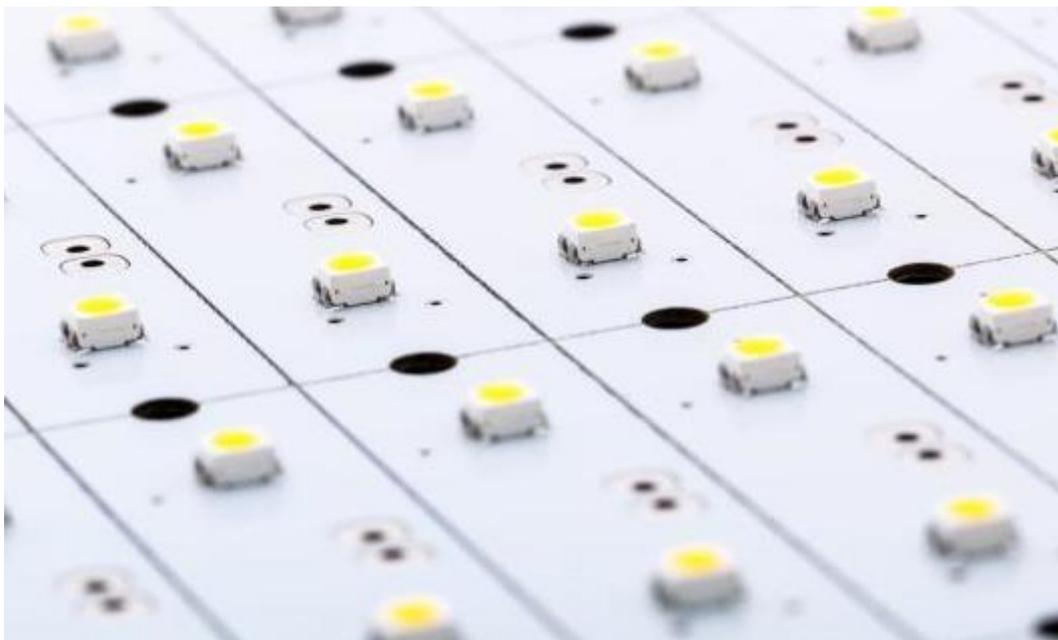
Recognised OEM Customers



FASTHERM®

New technology developed **by AISMALIBAR** to achieve a faster thermal transition from the LED thermal pad into the heat sink.

This superior thermal transition can be achieved by using the entire **COBRITHERM** HTC product range with either a Copper or Copper / Aluminium base.

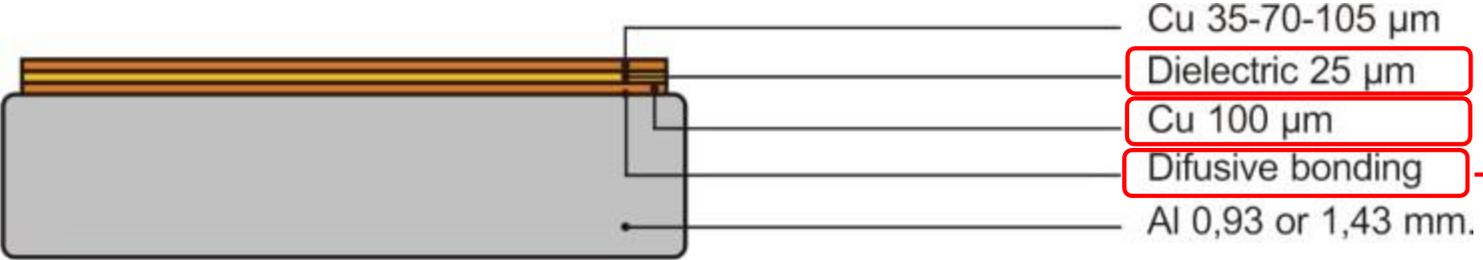


By using
AISMALIBAR
COBRITHERM HTC
range together with
FASTHERM
technology

LED's operate at
30°C to 50°C lower in
temperature due to
the direct thermal
transition from the
thermal pad to the
heatsink

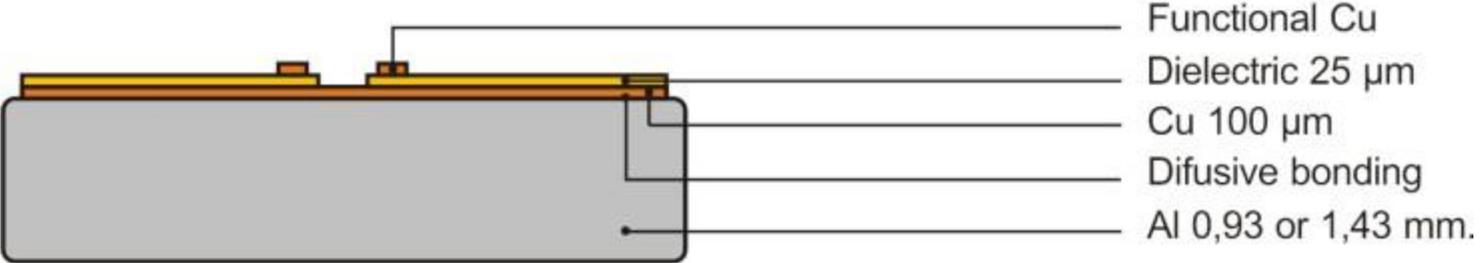
FASTHERM® COMPOSITIONS

Aluminium / Copper heat sink



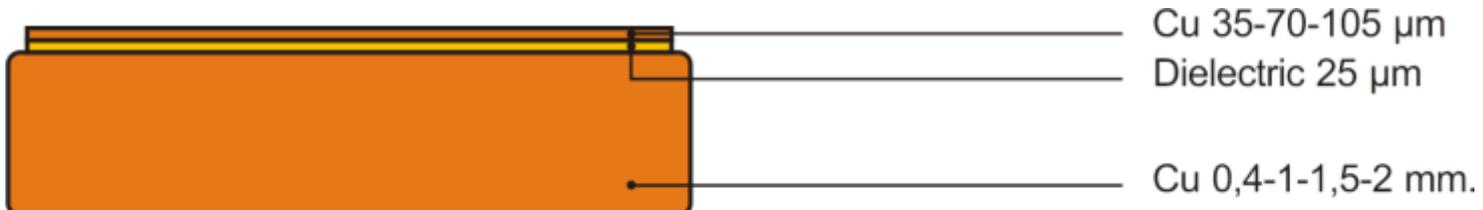
- Cu 35-70-105 µm
- Dielectric 25 µm
- Cu 100 µm
- Difusive bonding
- Al 0,93 or 1,43 mm.

Copper is bonded to aluminium with NO ADHESIVE

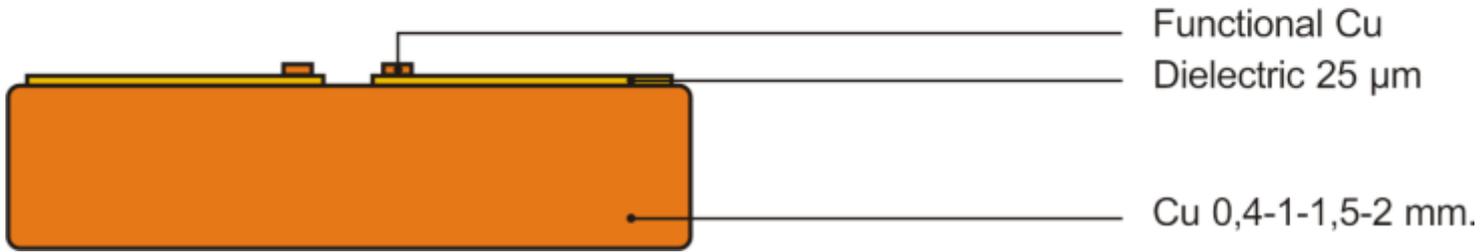


- Functional Cu
- Dielectric 25 µm
- Cu 100 µm
- Difusive bonding
- Al 0,93 or 1,43 mm.

Copper / Copper heat sink



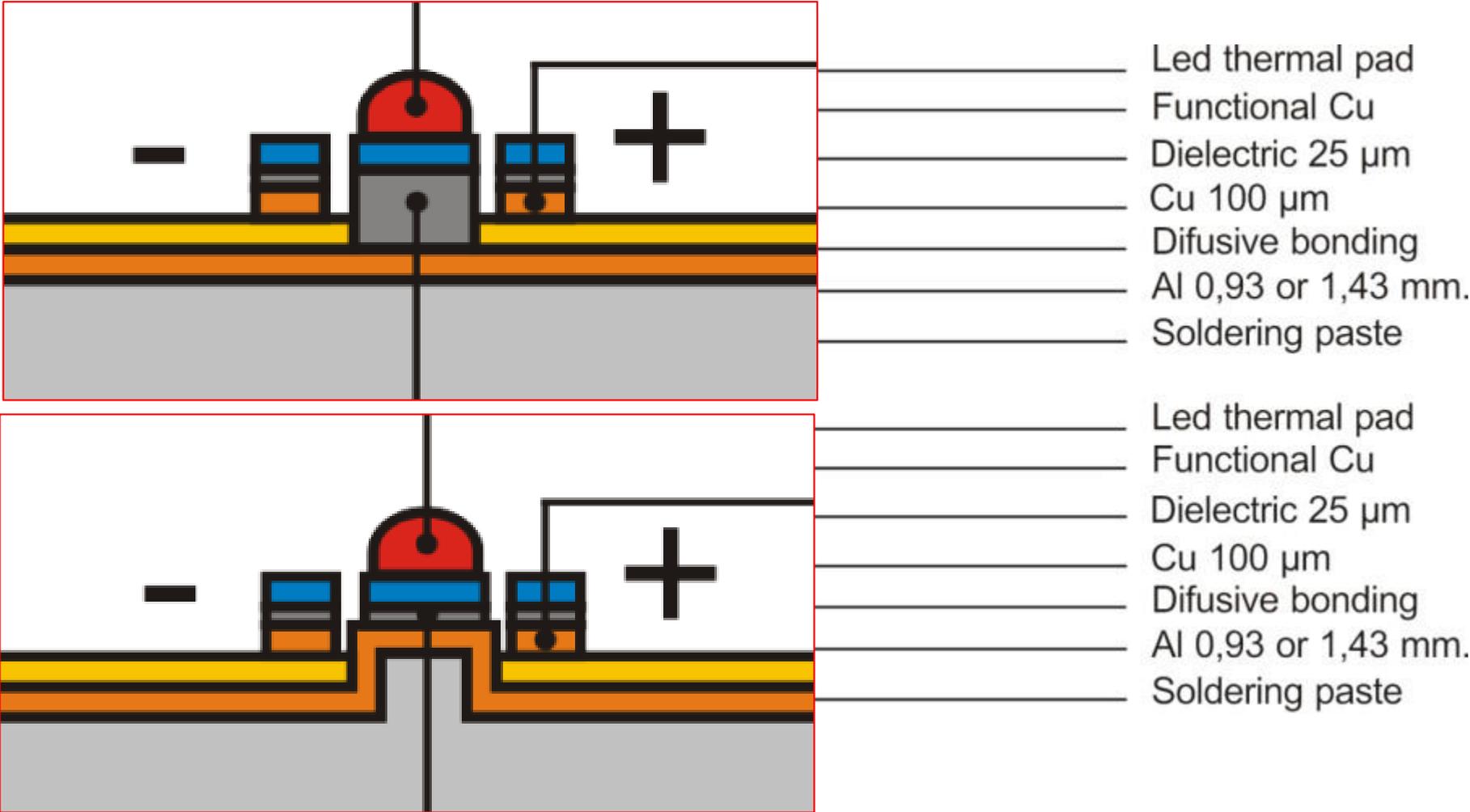
- Cu 35-70-105 µm
- Dielectric 25 µm
- Cu 0,4-1-1,5-2 mm.



- Functional Cu
- Dielectric 25 µm
- Cu 0,4-1-1,5-2 mm.

FASTHERM® COMPOSITIONS

Aluminium / Copper heat sink



MPCB - Constructions

FASTHERM® versus COBRITHERM®

	Composition					Dielectric Layer		IMS (Aluminum + dielectric + copper)				
	Aluminum		Copper (non functional)		Copper	Conductivity		Conductivity °C/W			Thermal Impedance	
	mm.	inch	mic	onz	mic	W/mK	W/inchK	W/mK	W/inchK	Kcm2/W	Kin2/W	°C/W
FASTHERM	1,43	0,056	100	2	70			132,8	3,374	0,118	0,018	0,039
ULTRATHIN	1,59	0,059	0	0	70	3,2	0,081	72,2	1,834	0,222	0,034	0,074
HTC 3,2w 90u	1,5	0,059	0	0	70	3,2	0,081	43,1	1,095	0,394	0,061	0,131
AlCuP	1,5	0,059	0	0	70	1,8	0,046	21,7	0,551	0,78	0,104	0,26
AlCuP-G	1,5	0,059	0	0	70	1,3	0,033	16,3	0,414	1,036	0,161	0,345

90%
Thermal resistance reduction

Bendable and conformable FLEXTHERM®

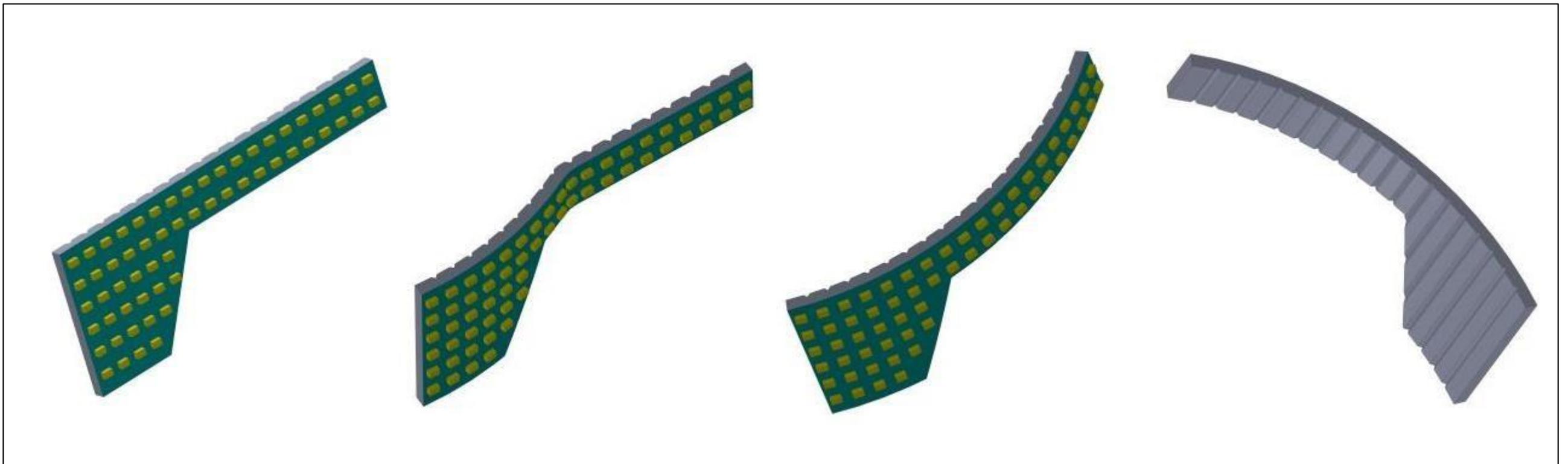
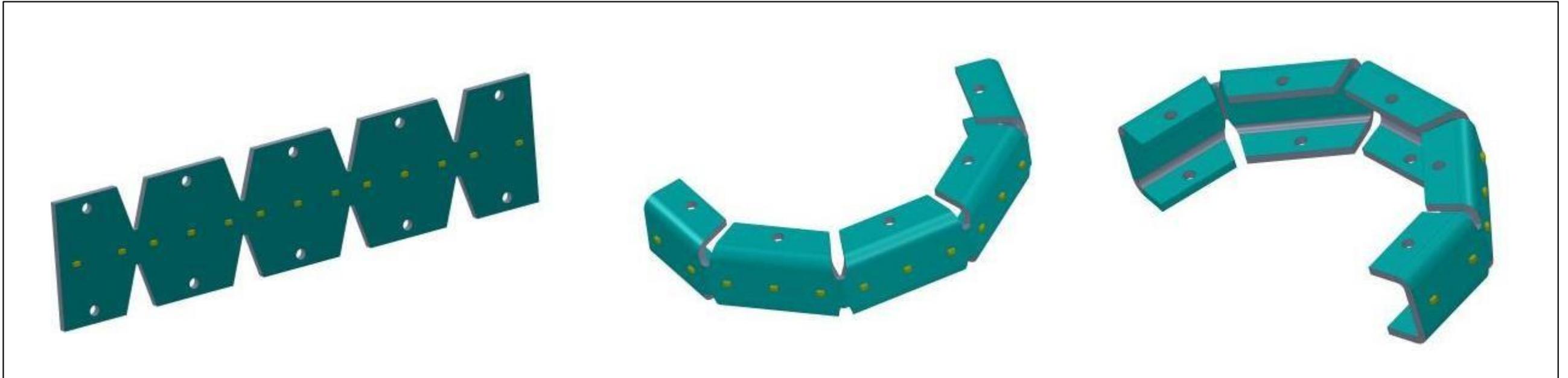
FLEXTHERM is ideal to produce conformable MPCB's which can be bent without compromising the initial dielectric strength between conductive layers. (Al and Cu).

The flexible properties of this material enable it to conform to both the negative and positive radius allowing the product to adapt to the ever changing demands of the industry.

Typical applications for FLEXTHERM are high power LED, power supply modules and the automotive industry.



Bendable and conformable FLEXTHERM®



DATA SHEET
FLEXTHERM

DS_160727

DESCRIPTION

Insulated Metal Substrate (IMS), based aluminum clad with RA copper foil on one or both sides. It is designed for the reliable thermal dissipation of circuitry.

FLEXTHERM is ideal for conformable MPCB manufacturing. It can be bent after MPCB production while maintaining the initial dielectric strength in between conductive layers (Al and Cu).

SPECIFICATIONS

- Withstands Lead Free Soldering process
- Excellent for high temperature components applications
- Extremely low thermal impedance
- V-0 Granted
- Halogen Free
- High MOT values
- Produced with RA copper to grant conformable properties

The material is supplied with a film on the aluminium side to protect it against wet PCB processes.

ROHS compliance directive 2002/95/EC and REACH N° 1907/2006 IPC-4101

STANDARD CONSTRUCTIONS

Aluminium thickness, μm (inch)	800 (0,032) - 1000 (0,039)– 1500 (0,059)	Aluminium Alloy / Treat	1050-3003 -5052-5754
Insulation thickness, μm	25 (0,98 mils) -35 (1.38 mils)	Dielectric thickness tolerance	+ 8 μm (0.1 mils)
RA copper thickness, μm	35 (1oz) – 70 (2oz)		
Other constructions available upon request			

PROPERTIES	TEST METHOD	UNITS	TYPICAL VALUES	Guaranteed values
1500 μm Al / 25 μm dielectric / 35 μm Cu				
Time to blister at 288°C, floating on solder (50 x 50 mm)	IEC-61180	sec	>60	>30
Copper Peel strength, after heat shock 20 sec/288°C	IPC-TM 650-2.4.8	N/mm (Lb/inch)	1,5 (10,0)	>1,0 (>10,3)
Dielectric breakdown voltage, AC (1) Flextherm 25 μm	IPC-TM 650-2.5.6.3	kV	2	2
Dielectric breakdown voltage, AC (1) Flextherm 35 μm			4	4
Thermal conductivity (dielectric layer)	ASTM-D 5470	W/mK (W/in-K)	0,7 (0,018)	0,6 (0,015)
Flammability, according UL-94, class	UL-94	Class	V-0	V-0
Thermal Impedance °C-m ² /watt Flextherm 25 μm	Calculated	Kcm ² /W (K in ² /W)	0,36 (0,055)	0,42 (0,065)
Thermal Impedance °C-m ² /watt Flextherm 35 μm			0,50 (0,078)	0,58 (0,090)
Maximum Operational Temperature		°C	140	130
Aluminium Thermal Conductivity	ASTM-D 5470	W/mK	135	130
Copper Thermal Conductivity	ASTM-D 5470	W/mK	375	380

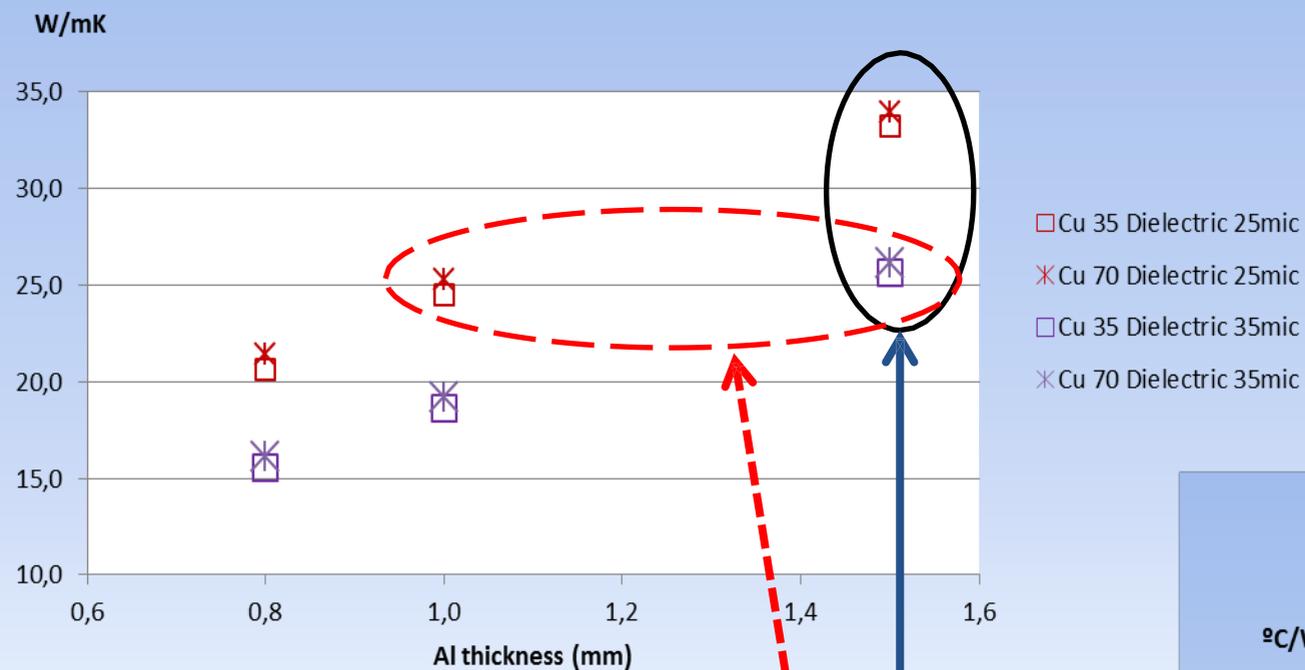
(*) Values or parameters measured with a destructive method or limited size for the test sample must be considered as a representative values, and not as guaranteed values. They are not guaranteed over 100% of the material.

Thermal impedance profile

THERMAL CONDUCTIVITY AND THERMAL IMPEDANCE														
Composition	Aluminium				Copper				Dielectric layer			IMS (Aluminium+dielectric+copper)		
	Aluminium	Copper			Thickness	Cond.		Rth	Cond.	Rth				
	mm	inch	mic	Onz	mic	(mil)	W/mK	°C/W	W/mK	Kinch2/W	°C/W			
Flextherm 25mic	0,8	0,031	35	1					20,6	0,065	0,139			
	0,8	0,031	70	2					21,4	0,065	0,139			
	1	0,039	35	2	25	1,0	0,7	0,119	24,5	0,067	0,144			
	1	0,039	70	2					25,3	0,067	0,144			
	1,5	0,059	35	1					33,3	0,073	0,156			
	1,5	0,059	70	2					33,9	0,073	0,157			
Flextherm 35mic	0,8	0,031	35	1					15,5	0,087	0,187			
	0,8	0,031	70	2					16,1	0,087	0,187			
	1	0,039	70	2	35	1,4	0,7	0,167	19,2	0,089	0,192			
	1	0,039	70	2					19,2	0,089	0,192			
	1,5	0,059	35	1					25,7	0,095	0,204			
	1,5	0,059	70	2					26,2	0,095	0,204			

Thermal impedance profile

Conductivity (W/mK) vs Flextherm built up

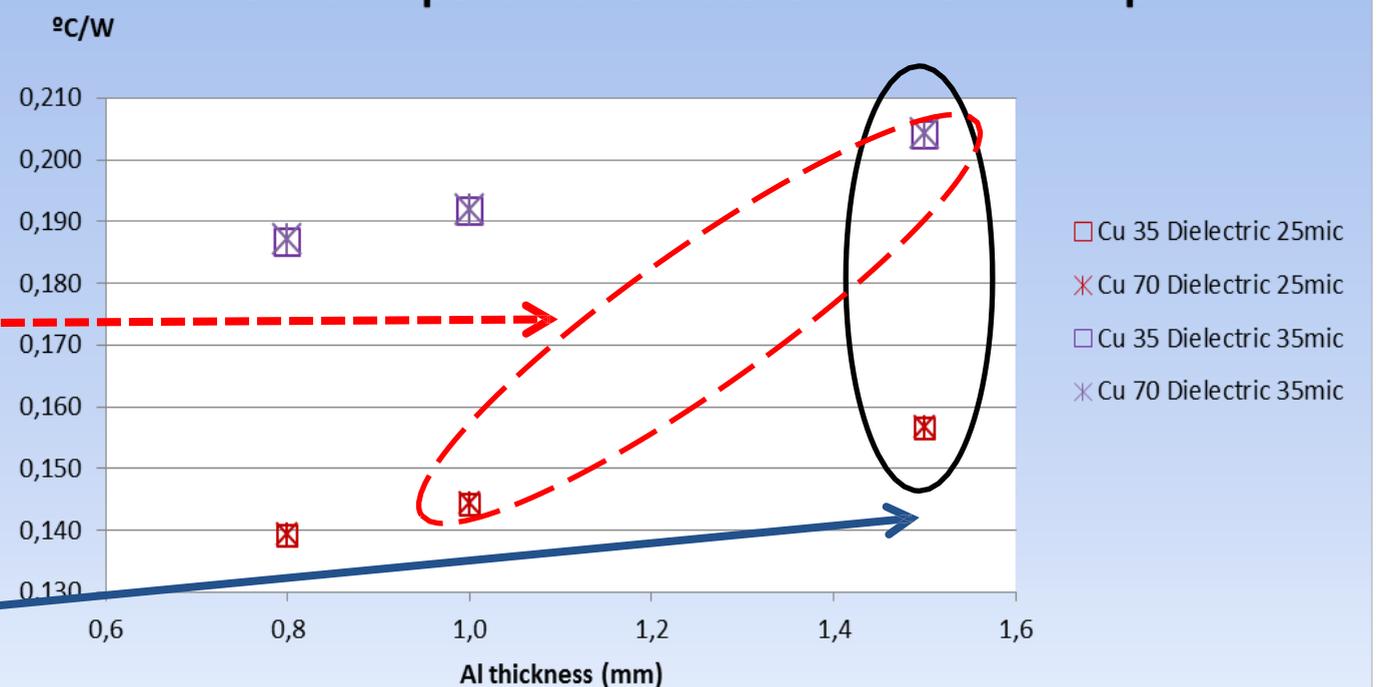


Thermal impedance is affected mainly by aluminum and dielectric thickness.

Copper thickness has practically no influence.

In spite of the thermal conductivity W/mK is higher or similar, due to the total thickness of the M-PCB, the final thermal resistance is worse.

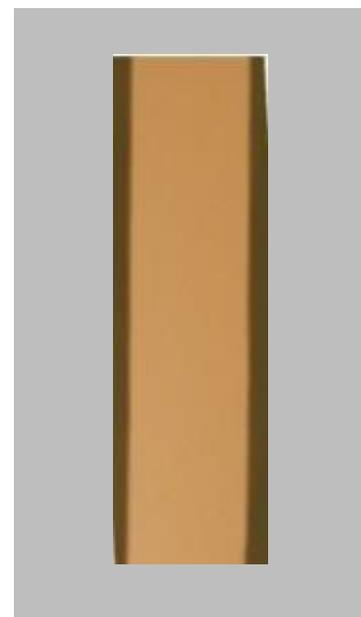
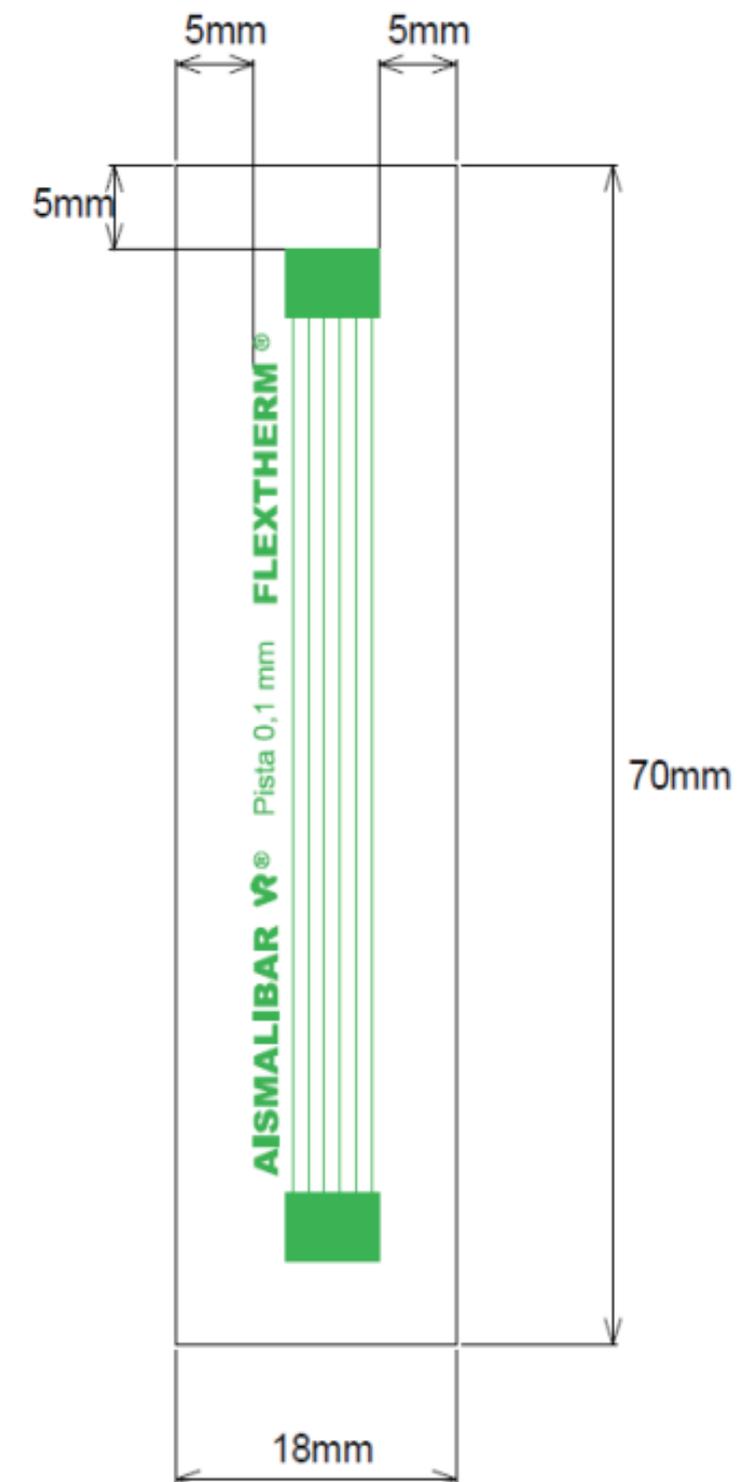
Rth (°C/W)
Thermal impedance vs Flextherm Al-Cu built up



Bending test

Sample construction:

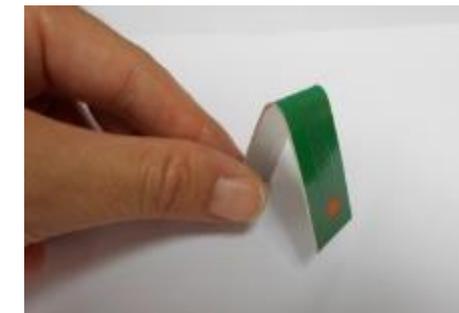
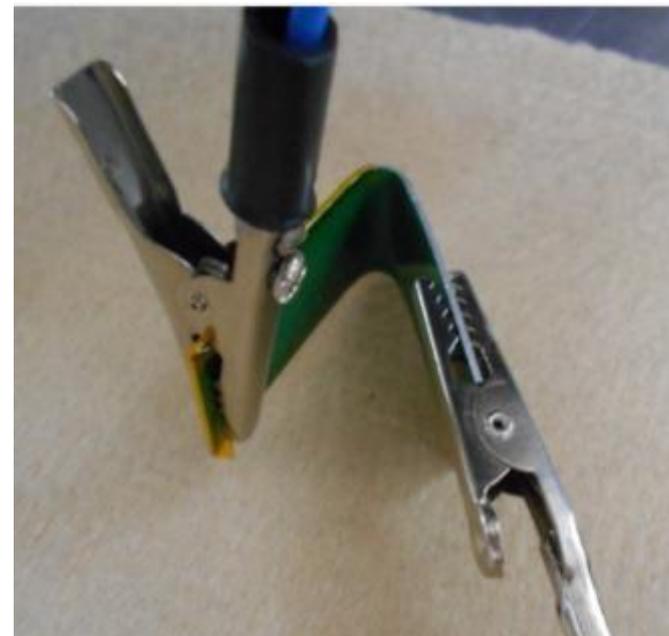
- Special design of the copper tracks has been carried out to evaluate the electrical isolation after several radii and bending angles.
- 35 and 70mic copper thickness were etched at 0,1mm to 1mm line width to study their fragility under positive and negative bending, as well as the tension produced over the dielectric layer at closed angles. Thinner the tracks, higher tension and more possibility for breaking the dielectric.
- Both dielectric thickness 25mic and 35mic, were tested.
- Full copper also was tested



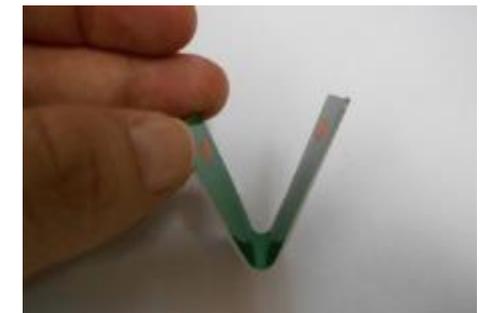
Bending test

Test:

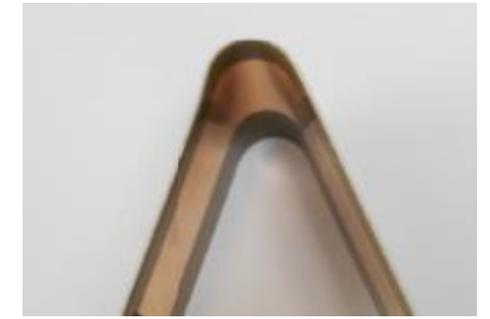
- Samples have been bended with positive and negative direction (copper inside and outside respectively).
- 1KV DC current is applied before and after bending (1KV maintenance 3sec).



POSITIVE BENDING



NEGATIVE BENDING



Bending test

1KV DC 3sec € 0.0mA Perfect electrical isolation

Mechanical stress € NO defect under visual inspection over Al, dielectric layer and Cu

Only Positive bending at radius $<1\text{mm}$ and $\geq 60^\circ$ breaks mechanically

FLEXTHERM 0,8/35 - NEGATIVE BENDING

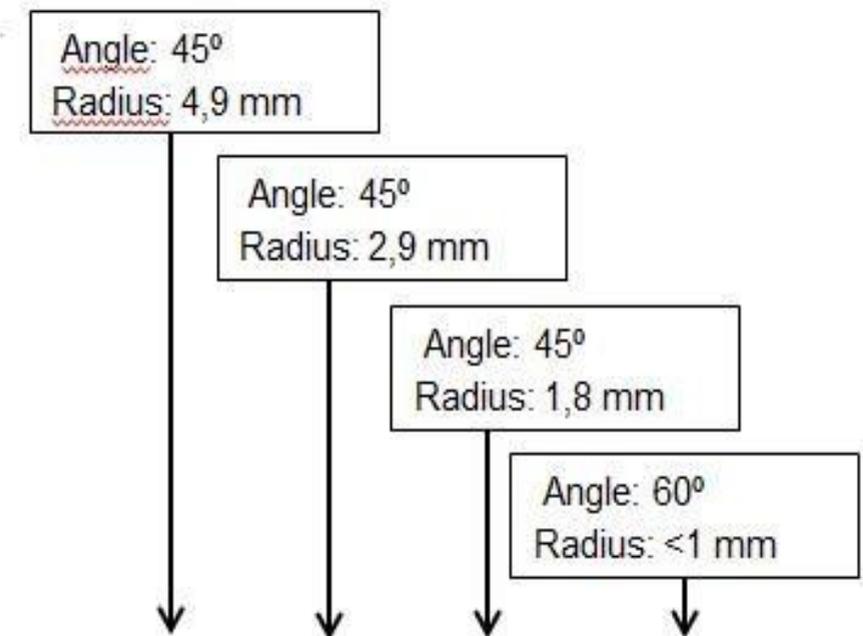
Angle	Radius (mm)	Width Copper tracks (mm)				
		0,2	0,3	0,4	0,5	1,0
45°	4,9	OK	OK	OK	OK	OK
	2,9	OK	OK	OK	OK	OK
	1,8	OK	OK	OK	OK	OK
60°	<1	OK	OK	OK	OK	OK

FLEXTHERM 0,8/35 - POSITIVE BENDING

Angle	Radius (mm)	Width Copper tracks (mm)				
		0,2	0,3	0,4	0,5	1,0
45°	4,9	OK	OK	OK	OK	OK
	2,9	OK	OK	OK	OK	OK
	1,8	OK	OK	OK	OK	OK
60°	<1	NOK	NOK	NOK	NOK	NOK

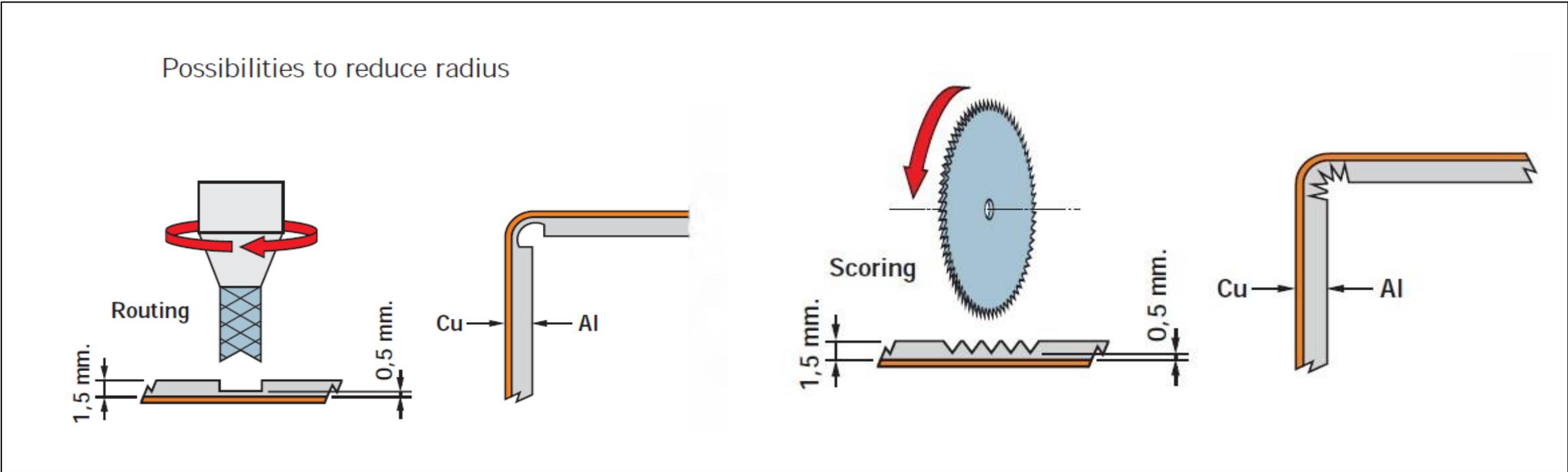
(1) Copper tracks as well as dielectric layer breaks

Note: Standard solder mask can have cracking problems.
Solder mask manufacturers can supply special solder mask for bendable porpoise.
Recommendation: PI cover layer is an ideal solution



FLEXTHERM® Orientative product applications

FLEXTHERM	Standard Construction (μ) Al / Dielectric / Cu	Dielectrical breakdown voltage AC	Orientative Applications
FLEXTHERM - 25	1.500 / 25 / 35 or 70	2.000 V	HiPo LEDs > 4 W. Medium Power applications, LEDs. Max. cost-effectiveness
FLEXTHERM - 35	1.500 / 35 / 35 or 70	4.000 V	High Power applications, DC Power converters



NEW HTC 4,0W

DATA SHEET

DS_170331

COBRITHERM HTC 4.0W 35µm ULTRA THIN LAYER (PROOF TEST 750V)

DESCRIPTION			
Insulated Metal Substrate (IMS), based aluminum clad with ED copper foil on the opposite side. It is designed for the reliable thermal dissipation of circuitry. A proprietary formulated polymer-ceramic ultra thin bonding layer with high thermal conductivity and dielectric strength allows us to guarantee thermal endurance.			
The material is supplied with a film on the aluminum side to protect it against wet PCB processes.			
ROHS compliance directive 2002/95/EC and REACH N° 1907/2006			
STANDARD CONSTRUCTIONS			
Aluminum thickness, m (in)	1000 (0.039) – 1500 (0.059)	Aluminum Alloy / Treat	5052
Insulation thickness, m	50 micron (2 mils)	Dielectric thickness tolerance	+ 15 micron (0,6 mils)
ED copper thickness, m	35 (1oz) – 70 (2oz) – 105 (3oz) - 210 (6oz)		
Other constructions available upon request			
UL Approved , QMTS2, QMTS8 File: E47820		IPC 4101	

(1) **Electrical proof test. 100% of our laminate production delivered, has been “on line” verified at 750v V_{dc}: 500 V/sec. ramp // 5sec.**

PROPERTIES 1500 m Al / 35 m dielectric / 70 m Cu	TEST METHOD	UNITS	TYPICAL VALUES	Values
Time to blister at 288°C, floating on solder (50 x 50 mm)	IEC-61189	Sec	>120	>60
Copper Peel strength, after heat shock 20 sec/288°C	IPC-TM 650-2.4.8	N/mm (Lb/in)	1,2 (16,0)	>1,0 (>10,3)
Dielectric breakdown voltage, AC (2)	IPC-TM 650-2.5.6.3	kV	2,5	>2,0
Proof Test, DC (1)	--	V	750	750
Thermal conductivity (dielectric layer)	ASTM-D 5470	W/mK (W/inK)	4,1 (0,104)	4,00 (0,102)
Thermal impedance (dielectric layer)	ASTM-D 5470	Kcm ² /W (Kin ² /W)	0,08 (0,013)	0,09 (0,014)
Flammability, according UL-94, class	UL-94	class	V-0	V-0
Glass transition temperature of dielectric layer (by TMA)	IPC-TM 650-2.4.24	°C	120	120
Maximum operating temperature	--	°C	150	150

(*) Values or parameters measured with a destructive method or limited size for the test sample must be considered as a representative values, and not as guaranteed values. They are not guaranteed over 100% of the material.

(2) **Dielectric Breakdown** test is a material destructive laboratory test. It is performed according the IPC-TM-650 part 2.5.6.3., by using AC voltage until electric failure on a relatively small surface area of the dielectric layer using metal electrodes. Values should be taken as a material reference and not as guaranteed values.

Success in automotive



COBRITHERM[®] ULTRATHIN 35 μ

Success in automotive

COBRITHERM®



Mercedes-Benz



Many Top manufacturers trust in our products
C- Class



Many Top manufacturers trust in our products
VW – Touran

Success in automotive

COBRITHERM®



Many Top manufacturers trust in our products

BMW

7 Series & 6 Series



RENAULT



New car models in 2016

New Clio 2016



Audi



New car models in 2016

Audi- Q-3

Audi- Q-5

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